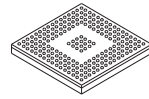


## MCF547x ColdFire® Microprocessor

Supports MCF5470, MCF5471,  
MCF5472, MCF5473, MCF5474, and  
MCF5475

## MCF547x



TEPBGA-388  
27 mm x 27 mm

### Features list:

- ColdFire V4e Core
  - Limited superscalar V4 ColdFire processor core
  - Up to 266 MHz peak internal core frequency (410 MIPS [Dhrystone 2.1] @ 266 MHz)
  - Harvard architecture
    - 32-Kbyte instruction cache
    - 32-Kbyte data cache
  - Memory Management Unit (MMU)
    - Separate, 32-entry, fully-associative instruction and data translation lookahead buffers
  - Floating point unit (FPU)
    - Double-precision conforms to IEEE-754 standard
    - Eight floating point registers
- Internal master bus (XLB) arbiter
  - High performance split address and data transactions
  - Support for various parking modes
- 32-bit double data rate (DDR) synchronous DRAM (SDRAM) controller
  - 66–133 MHz operation
  - Supports DDR and SDR DRAM
  - Built-in initialization and refresh
  - Up to four chip selects enabling up to one GB of external memory
- Version 2.2 peripheral component interconnect (PCI) bus
  - 32-bit target and initiator operation
  - Support for up to five external PCI masters
  - 33–66 MHz operation with PCI bus to XLB divider ratios of 1:1, 1:2, and 1:4
- Flexible multi-function external bus (FlexBus)
  - Provides a glueless interface to boot flash/ROM, SRAM, and peripheral devices
  - Up to six chip selects
  - 33 – 66 MHz operation
- Communications I/O subsystem
  - Intelligent 16 channel DMA controller
  - Up to two 10/100 Mbps fast Ethernet controllers (FECs) each with separate 2-Kbyte receive and transmit FIFOs
  - Universal serial bus (USB) version 2.0 device controller
    - Support for one control and six programmable endpoints, interrupt, bulk, or isochronous
  - 4-Kbytes of shared endpoint FIFO RAM and 1 Kbyte of endpoint descriptor RAM
  - Integrated physical layer interface
- Up to four programmable serial controllers (PSCs) each with separate 512-byte receive and transmit FIFOs for UART, USART, modem, codec, and IrDA 1.1 interfaces
- I<sup>2</sup>C peripheral interface
- DMA Serial Peripheral Interface (DSPI)
- Optional Cryptography accelerator module
  - Execution units for:
    - DES/3DES block cipher
    - AES block cipher
    - RC4 stream cipher
    - MD5/SHA-1/SHA-256/HMAC hashing
    - Random Number Generator
- 32-Kbyte system SRAM
  - Arbitration mechanism shares bandwidth between internal bus masters
- System integration unit (SIU)
  - Interrupt controller
  - Watchdog timer
  - Two 32-bit slice timers alarm and interrupt generation
  - Up to four 32-bit general-purpose timers, compare, and PWM capability
  - GPIO ports multiplexed with peripheral pins
- Debug and test features
  - ColdFire background debug mode (BDM) port
  - JTAG/ IEEE 1149.1 test access port
- PLL and clock generator
  - 30 to 66.67 MHz input frequency range
- Operating Voltages
  - 1.5V internal logic
  - 2.5V DDR SDRAM bus I/O
  - 3.3V PCI, FlexBus, and all other I/O
- Estimated power consumption
  - Less than 1.5W (388 PBGA)

# Table of Contents

|      |                                                     |    |
|------|-----------------------------------------------------|----|
| 1    | Maximum Ratings                                     | 4  |
| 2    | Thermal Characteristics                             | 4  |
| 2.1  | Operating Temperatures                              | 4  |
| 2.2  | Thermal Resistance                                  | 4  |
| 3    | DC Electrical Specifications                        | 5  |
| 4    | Hardware Design Considerations                      | 6  |
| 4.1  | PLL Power Filtering                                 | 6  |
| 4.2  | Supply Voltage Sequencing and Separation Cautions   | 6  |
| 4.3  | General USB Layout Guidelines                       | 8  |
| 4.4  | USB Power Filtering                                 | 9  |
| 5    | Output Driver Capability and Loading                | 10 |
| 6    | PLL Timing Specifications                           | 11 |
| 7    | Reset Timing Specifications                         | 12 |
| 8    | FlexBus                                             | 12 |
| 8.1  | FlexBus AC Timing Characteristics                   | 13 |
| 9    | SDRAM Bus                                           | 15 |
| 9.1  | SDR SDRAM AC Timing Characteristics                 | 15 |
| 9.2  | DDR SDRAM AC Timing Characteristics                 | 18 |
| 10   | PCI Bus                                             | 21 |
| 11   | Fast Ethernet AC Timing Specifications              | 22 |
| 11.1 | MII/7-WIRE Interface Timing Specs                   | 22 |
| 11.2 | MII Transmit Signal Timing                          | 23 |
| 11.3 | MII Async Inputs Signal Timing (CRS, COL)           | 24 |
| 11.4 | MII Serial Management Channel Timing (MDIO, MDC)    | 24 |
| 12   | General Timing Specifications                       | 25 |
| 13   | I <sup>2</sup> C Input/Output Timing Specifications | 25 |
| 14   | JTAG and Boundary Scan Timing                       | 26 |
| 15   | DSPI Electrical Specifications                      | 29 |
| 16   | Timer Module AC Timing Specifications               | 29 |
| 17   | Case Drawing                                        | 30 |
| 18   | Revision History                                    | 32 |

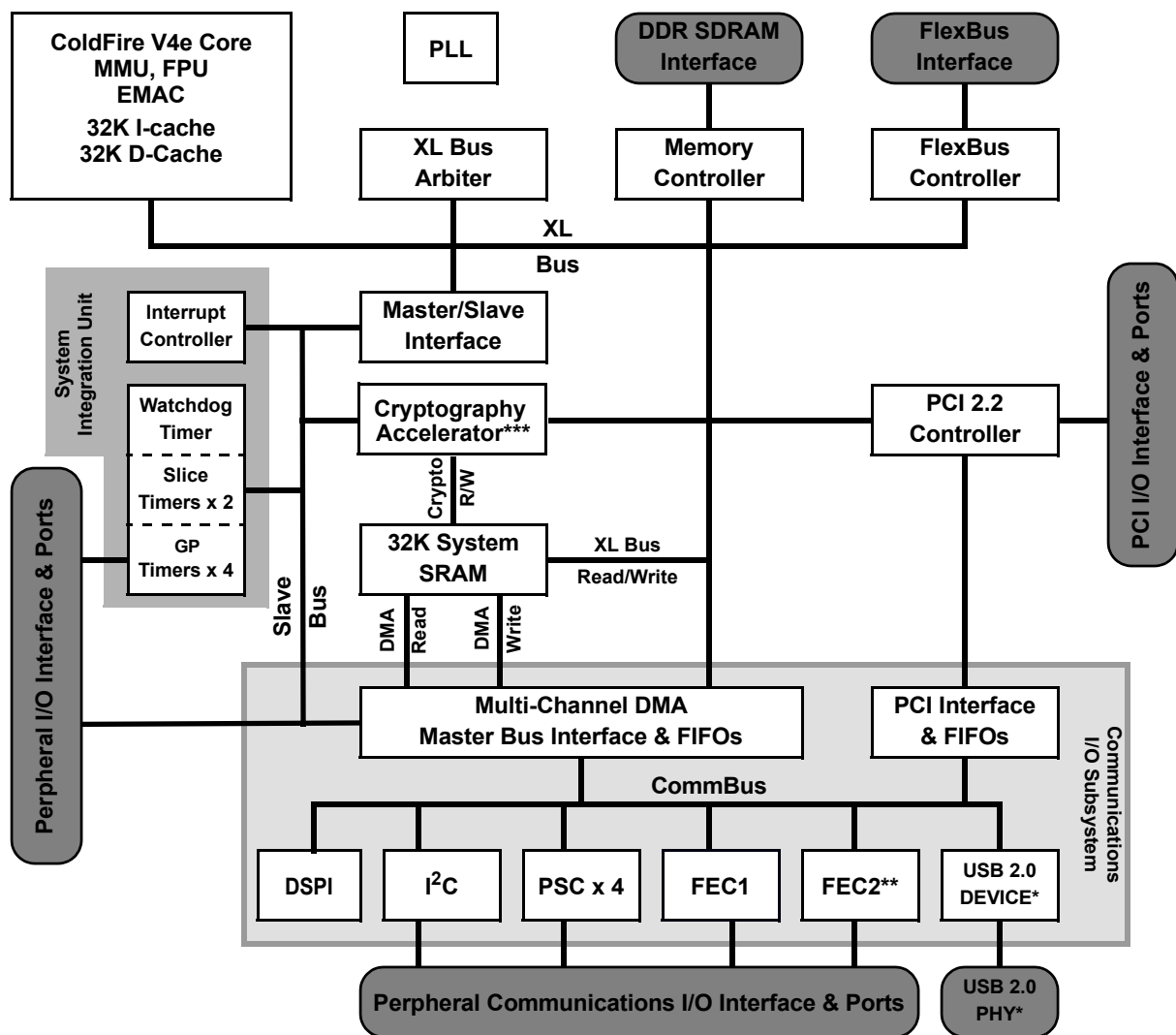
## List of Figures

|            |                                                   |    |
|------------|---------------------------------------------------|----|
| Figure 1.  | MCF547X Block Diagram                             | 3  |
| Figure 2.  | System PLL V <sub>DD</sub> Power Filter           | 6  |
| Figure 3.  | Supply Voltage Sequencing and Separation Cautions | 7  |
| Figure 4.  | Preferred VBUS Connections                        | 8  |
| Figure 5.  | Alternate VBUS Connections                        | 8  |
| Figure 6.  | USB V <sub>DD</sub> Power Filter                  | 9  |
| Figure 7.  | USBRBIAS Connection                               | 10 |
| Figure 8.  | Input Clock Timing Diagram                        | 11 |
| Figure 9.  | CLKIN, Internal Bus, and Core Clock Ratios        | 11 |
| Figure 10. | Reset Timing                                      | 12 |
| Figure 11. | FlexBus Read Timing                               | 14 |
| Figure 12. | FlexBus Write Timing                              | 15 |
| Figure 13. | SDR Write Timing                                  | 17 |
| Figure 14. | SDR Read Timing                                   | 17 |

|            |                                              |    |
|------------|----------------------------------------------|----|
| Figure 15. | DDR Clock Timing Diagram                     | 18 |
| Figure 16. | DDR Write Timing                             | 20 |
| Figure 17. | DDR Read Timing                              | 21 |
| Figure 18. | PCI Timing                                   | 22 |
| Figure 19. | MII Receive Signal Timing Diagram            | 23 |
| Figure 20. | MII Transmit Signal Timing Diagram           | 23 |
| Figure 21. | MII Async Inputs Timing Diagram              | 24 |
| Figure 22. | MII Serial Management Channel Timing Diagram | 24 |
| Figure 23. | I <sup>2</sup> C Input/Output Timings        | 26 |
| Figure 24. | Test Clock Input Timing                      | 27 |
| Figure 25. | Boundary Scan (JTAG) Timing                  | 27 |
| Figure 26. | Test Access Port Timing                      | 27 |
| Figure 27. | TRST Timing Debug AC Timing Specifications   | 27 |
| Figure 28. | Real-Time Trace AC Timing                    | 28 |
| Figure 29. | BDM Serial Port AC Timing                    | 28 |
| Figure 30. | DSPI Timing                                  | 29 |
| Figure 31. | 388-pin BGA Case Outline                     | 31 |

## List of Tables

|           |                                                                      |    |
|-----------|----------------------------------------------------------------------|----|
| Table 1.  | Absolute Maximum Ratings                                             | 4  |
| Table 2.  | Operating Temperatures                                               | 4  |
| Table 3.  | Thermal Resistance                                                   | 4  |
| Table 4.  | DC Electrical Specifications                                         | 5  |
| Table 5.  | USB Filter Circuit Values                                            | 9  |
| Table 6.  | I/O Driver Capability                                                | 10 |
| Table 7.  | Clock Timing Specifications                                          | 11 |
| Table 8.  | MCF547x Divide Ratio Encodings                                       | 11 |
| Table 9.  | Reset Timing Specifications                                          | 12 |
| Table 10. | FlexBus AC Timing Specifications                                     | 13 |
| Table 11. | SDR Timing Specifications                                            | 16 |
| Table 12. | DDR Clock Crossover Specifications                                   | 18 |
| Table 13. | DDR Timing Specifications                                            | 18 |
| Table 14. | PCI Timing Specifications                                            | 21 |
| Table 15. | MII Receive Signal Timing                                            | 23 |
| Table 16. | MII Transmit Signal Timing                                           | 23 |
| Table 17. | MII Transmit Signal Timing                                           | 24 |
| Table 18. | MII Serial Management Channel Signal Timing                          | 24 |
| Table 19. | General AC Timing Specifications                                     | 25 |
| Table 20. | I <sup>2</sup> C Input Timing Specifications between<br>SCL and SDA  | 25 |
| Table 21. | I <sup>2</sup> C Output Timing Specifications between<br>SCL and SDA | 25 |
| Table 22. | JTAG and Boundary Scan Timing                                        | 26 |
| Table 23. | Debug AC Timing Specifications                                       | 28 |
| Table 24. | DSPI Modules AC Timing Specifications                                | 29 |
| Table 25. | Timer Module AC Timing Specifications                                | 29 |



### Figure 1. MCF547X Block Diagram

# 1 Maximum Ratings

Table 1 lists maximum and minimum ratings for supply and operating voltages and storage temperature. Operating outside of these ranges may cause erratic behavior or damage to the processor.

**Table 1. Absolute Maximum Ratings**

| Rating                                                | Symbol       | Value                                              | Units |
|-------------------------------------------------------|--------------|----------------------------------------------------|-------|
| External (I/O pads) supply voltage (3.3-V power pins) | $EV_{DD}$    | −0.3 to +4.0                                       | V     |
| Internal logic supply voltage                         | $IV_{DD}$    | −0.5 to +2.0                                       | V     |
| Memory (I/O pads) supply voltage (2.5-V power pins)   | $SD V_{DD}$  | −0.3 to +4.0 SDR Memory<br>−0.3 to +2.8 DDR Memory | V     |
| PLL supply voltage                                    | $PLL V_{DD}$ | −0.5 to +2.0                                       | V     |
| Internal logic supply voltage, input voltage level    | $V_{in}$     | −0.5 to +3.6                                       | V     |
| Storage temperature range                             | $T_{stg}$    | −55 to +150                                        | °C    |

## 2 Thermal Characteristics

### 2.1 Operating Temperatures

Table 2 lists junction and ambient operating temperatures.

**Table 2. Operating Temperatures**

| Characteristic                         | Symbol     | Value            | Units |
|----------------------------------------|------------|------------------|-------|
| Maximum operating junction temperature | $T_j$      | 105              | °C    |
| Maximum operating ambient temperature  | $T_{Amax}$ | <70 <sup>1</sup> | °C    |
| Minimum operating ambient temperature  | $T_{Amin}$ | −0               | °C    |

<sup>1</sup> This published maximum operating ambient temperature should be used only as a system design guideline. All device operating parameters are guaranteed only when the junction temperature lies within the specified range.

### 2.2 Thermal Resistance

Table 3 lists thermal resistance values.

**Table 3. Thermal Resistance**

| Characteristic                                           | Symbol         | Value                | Unit |
|----------------------------------------------------------|----------------|----------------------|------|
| 324 pin TEPBGA — Junction to ambient, natural convection | $\theta_{JMA}$ | 20–22 <sup>1,2</sup> | °CW  |
| 388 pin TEPBGA — Junction to ambient, natural convection | $\theta_{JMA}$ | 19 <sup>1,2</sup>    | °CW  |

Table 3. Thermal Resistance (continued)

| Characteristic                    |                         | Symbol         | Value             | Unit |
|-----------------------------------|-------------------------|----------------|-------------------|------|
| Junction to ambient (@200 ft/min) | Four layer board (2s2p) | $\theta_{JMA}$ | 16 <sup>1,2</sup> | °CW  |
| Junction to board                 | —                       | $\theta_{JB}$  | 11 <sup>3</sup>   | °CW  |
| Junction to case                  | —                       | $\theta_{JC}$  | 7 <sup>4</sup>    | °CW  |
| Junction to top of package        | Natural convection      | $\Psi_{jt}$    | 2 <sup>1,5</sup>  | °CW  |

<sup>1</sup>  $\theta_{JA}$  and  $\Psi_{jt}$  parameters are simulated in accordance with EIA/JESD Standard 51-2 for natural convection. Freescale recommends the use of  $\theta_{JA}$  and power dissipation specifications in the system design to prevent device junction temperatures from exceeding the rated specification. System designers should be aware that device junction temperatures can be significantly influenced by board layout and surrounding devices. Conformance to the device junction temperature specification can be verified by physical measurement in the customer's system using the  $\Psi_{jt}$  parameter, the device power dissipation, and the method described in EIA/JESD Standard 51-2.

<sup>2</sup> Per JEDEC JESD51-6 with the board horizontal.

<sup>3</sup> Thermal resistance between the die and the printed circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.

<sup>4</sup> Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1).

<sup>5</sup> Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2. When Greek letters are not available, the thermal characterization parameter is written as Psi-JT.

### 3 DC Electrical Specifications

Table 4 lists DC electrical operating temperatures. This table is based on an operating voltage of  $EV_{DD} = 3.3 V_{DC} \pm 0.3 V_{DC}$  and  $IV_{DD}$  of  $1.5 \pm 0.07 V_{DC}$ .

Table 4. DC Electrical Specifications

| Characteristic                                         | Symbol            | Min                  | Max                   | Units |
|--------------------------------------------------------|-------------------|----------------------|-----------------------|-------|
| External (I/O pads) operation voltage range            | $EV_{DD}$         | 3.0                  | 3.6                   | V     |
| Memory (I/O pads) operation voltage range (DDR Memory) | $SD V_{DD}$       | 2.30                 | 2.70                  | V     |
| Internal logic operation voltage range <sup>1</sup>    | $IV_{DD}$         | 1.43                 | 1.58                  | V     |
| PLL Analog operation voltage range <sup>1</sup>        | $PLL V_{DD}$      | 1.43                 | 1.58                  | V     |
| USB oscillator operation voltage range                 | $USB\_OSV_{DD}$   | 3.0                  | 3.6                   | V     |
| USB digital logic operation voltage range              | $USBV_{DD}$       | 3.0                  | 3.6                   | V     |
| USB PHY operation voltage range                        | $USB\_PHYV_{DD}$  | 3.0                  | 3.6                   | V     |
| USB oscillator analog operation voltage range          | $USB\_OSCAV_{DD}$ | 1.43                 | 1.58                  | V     |
| USB PLL operation voltage range                        | $USB\_PLLV_{DD}$  | 1.43                 | 1.58                  | V     |
| Input high voltage SSTL 3.3V/2.5V <sup>2</sup>         | $V_{IH}$          | $V_{REF} + 0.3$      | $SD V_{DD} + 0.3$     | V     |
| Input low voltage SSTL 3.3V/2.5V <sup>2</sup>          | $V_{IL}$          | $V_{SS} - 0.3$       | $V_{REF} - 0.3$       | V     |
| Input high voltage 3.3V I/O pins                       | $V_{IH}$          | $0.7 \times EV_{DD}$ | $EV_{DD} + 0.3$       | V     |
| Input low voltage 3.3V I/O pins                        | $V_{IL}$          | $V_{SS} - 0.3$       | $0.35 \times EV_{DD}$ | V     |

**Table 4. DC Electrical Specifications (continued)**

| Characteristic                                                          | Symbol   | Min  | Max | Units         |
|-------------------------------------------------------------------------|----------|------|-----|---------------|
| Output high voltage $I_{OH} = 8\text{ mA}, 16\text{ mA}, 24\text{ mA}$  | $V_{OH}$ | 2.4  | —   | V             |
| Output low voltage $I_{OL} = 8\text{ mA}, 16\text{ mA}, 24\text{ mA}^5$ | $V_{OL}$ | —    | 0.5 | V             |
| Capacitance <sup>3</sup> , $V_{in} = 0\text{ V}$ , $f = 1\text{ MHz}$   | $C_{IN}$ | —    | TBD | pF            |
| Input leakage current                                                   | $I_{in}$ | -1.0 | 1.0 | $\mu\text{A}$ |

<sup>1</sup>  $IV_{DD}$  and PLL  $V_{DD}$  should be at the same voltage. PLL  $V_{DD}$  should have a filtered input. Please see [Figure 2](#) for an example circuit. There are three PLL  $V_{DD}$  inputs. A filter circuit should be used on each PLL  $V_{DD}$  input.

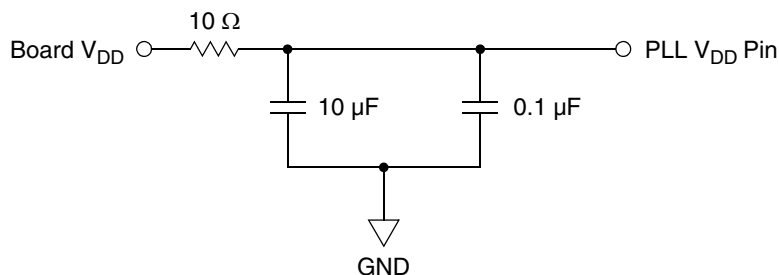
<sup>2</sup> This specification is guaranteed by design and is not 100% tested.

<sup>3</sup> Capacitance  $C_{IN}$  is periodically sampled rather than 100% tested.

## 4 Hardware Design Considerations

### 4.1 PLL Power Filtering

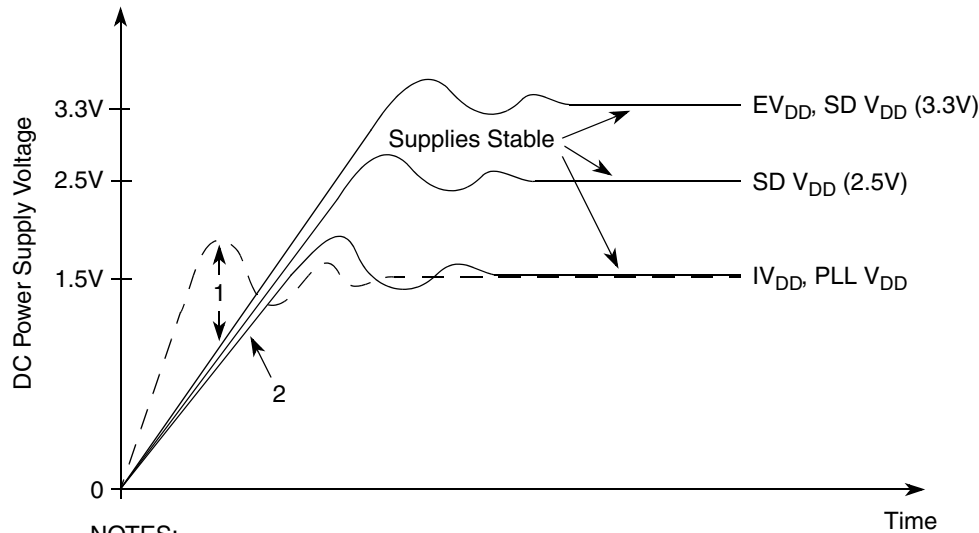
To further enhance noise isolation, an external filter is strongly recommended for PLL analog  $V_{DD}$  pins. The filter shown in [Figure 2](#) should be connected between the board  $V_{DD}$  and the PLL  $V_{DD}$  pins. The resistor and capacitors should be placed as close to the dedicated PLL  $V_{DD}$  pin as possible.



**Figure 2. System PLL  $V_{DD}$  Power Filter**

### 4.2 Supply Voltage Sequencing and Separation Cautions

[Figure 3](#) shows situations in sequencing the I/O  $V_{DD}$  ( $EV_{DD}$ ), SDRAM  $V_{DD}$  ( $SD V_{DD}$ ), PLL  $V_{DD}$  ( $PLL V_{DD}$ ), and Core  $V_{DD}$  ( $IV_{DD}$ ).



#### NOTES:

1.  $IV_{DD}$  should not exceed  $EV_{DD}$  or  $SD V_{DD}$  by more than 0.4V at any time, including power-up.
2. Recommended that  $IV_{DD}/PLL V_{DD}$  should track  $EV_{DD}/SD V_{DD}$  up to 0.9V, then separate for completion of ramps.
3. Input voltage must not be greater than the supply voltage ( $EV_{DD}$ ,  $SD V_{DD}$ ,  $IV_{DD}$ , or  $PLL V_{DD}$ ) by more than 0.5V at any time, including during power-up.
4. Use 1 microsecond or slower rise time for all supplies.

**Figure 3. Supply Voltage Sequencing and Separation Cautions**

The relationship between  $SD V_{DD}$  and  $EV_{DD}$  is non-critical during power-up and power-down sequences.  $SD V_{DD}$  (2.5V or 3.3V) and  $EV_{DD}$  are specified relative to  $IV_{DD}$ .

## 4.2.1 Power Up Sequence

If  $EV_{DD}/SD V_{DD}$  are powered up with the  $IV_{DD}$  at 0V, the sense circuits in the I/O pads cause all pad output drivers connected to the  $EV_{DD}/SD V_{DD}$  to be in a high impedance state. There is no limit to how long after  $EV_{DD}/SD V_{DD}$  powers up before  $IV_{DD}$  must power up.  $IV_{DD}$  should not lead the  $EV_{DD}$ ,  $SD V_{DD}$ , or  $PLL V_{DD}$  by more than 0.4V during power ramp up or there is high current in the internal ESD protection diodes. The rise times on the power supplies should be slower than 1 microsecond to avoid turning on the internal ESD protection clamp diodes.

The recommended power up sequence is as follows:

1. Use 1 microsecond or slower rise time for all supplies.
2.  $IV_{DD}/PLL V_{DD}$  and  $EV_{DD}/SD V_{DD}$  should track up to 0.9V, then separate for the completion of ramps with  $EV_{DD}/SD V_{DD}$  going to the higher external voltages. One way to accomplish this is to use a low drop-out voltage regulator.

## 4.2.2 Power Down Sequence

If  $IV_{DD}/PLL V_{DD}$  are powered down first, sense circuits in the I/O pads cause all output drivers to be in a high impedance state. There is no limit on how long after  $IV_{DD}$  and  $PLL V_{DD}$  power down before  $EV_{DD}$  or  $SD V_{DD}$  must power down.  $IV_{DD}$  should not lag  $EV_{DD}$ ,  $SD V_{DD}$ , or  $PLL V_{DD}$  going low by more than 0.4V during power down or there is undesired high current in the ESD protection diodes. There are no requirements for the fall times of the power supplies.

The recommended power down sequence is as follows:

1. Drop  $IV_{DD}/PLL V_{DD}$  to 0V
2. Drop  $EV_{DD}/SD V_{DD}$  supplies

## 4.3 General USB Layout Guidelines

### 4.3.1 USB D+ and D- High-Speed Traces

1. High speed clock and the USBD+ and USBD- differential pair should be routed first.
2. Route USBD+ and USBD- signals on the top layer of the board.
3. The trace width and spacing of the USBD+ and USBD- signals should be such that the differential impedance is  $90\Omega$ .
4. Route traces over continuous planes (power and ground)—they should not pass over any power/ground plane slots or anti-etch. When placing connectors, make sure the ground plane clear-outs around each pin have ground continuity between all pins.
5. Maintain the parallelism (skew matched) between USBD+ and USBD-. These traces should be the same overall length.
6. Do not route USBD+ and USBD- traces under oscillators or parallel to clock traces and/or data buses. Minimize the lengths of high speed signals that run parallel to the USBD+ and USBD- pair. Maintain a minimum 50mil spacing to clock signals.
7. Keep USBD+ and USBD- traces as short as possible.
8. Route USBD+, USBD-, and USBVBUS signals with a minimum amount of vias and corners. Use  $45^\circ$  turns.
9. Stubs should be avoided as much as possible. If they cannot be avoided, stubs should be no greater than 200mils.

### 4.3.2 USB VBUS Traces

Connecting the USBVBUS pin directly to the 5V VBUS signal from the USB connector can cause long-term reliability problems in the ESD network of the processor. Therefore, use of an external voltage divider for VBUS is recommended. [Figure 4](#) and [Figure 5](#) depict possible connections for VBUS. Point A, marked in each figure, is where a 5V version of VBUS should connect. Point B, marked in each figure, is where a 3.3V version of VBUS should connect to the USBVBUS pin on the device.

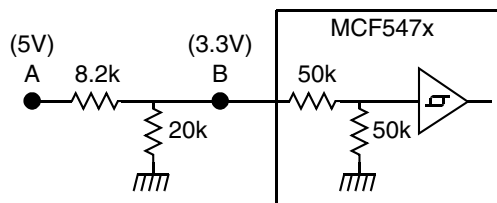


Figure 4. Preferred VBUS Connections

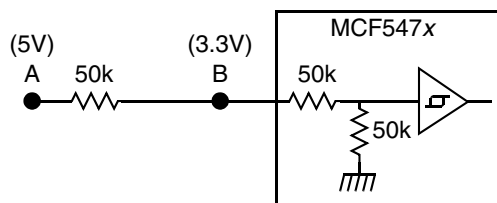


Figure 5. Alternate VBUS Connections

### 4.3.3 USB Receptacle Connections

It is recommended to connect the shield and the ground pin of the B USB receptacle for upstream ports to the board ground plane. The ground pin of the A USB receptacles for downstream ports should also be connected to the board ground plane, but industry practice varies widely on the connection of the shield of the A USB receptacles to other system grounds. Take precautions for control of ground loops between hosts and self-powered USB devices through the cable shield.

## 4.4 USB Power Filtering

To minimize noise, an external filter is required for each of the USB power pins. The filter shown in Figure 6 should be connected between the board  $EV_{DD}$  or  $IV_{DD}$  and each of the USB  $V_{DD}$  pins.

- The resistor and capacitors should be placed as close to the dedicated USB  $V_{DD}$  pin as possible.
- A separate filter circuit should be included for each USB  $V_{DD}$  pin, a total of five circuits.
- All traces should be as low impedance as possible, especially ground pins to the ground plane.
- The filter for USB\_PHYVDD to VSS should be connected to the power and ground planes, respectively, not fingers of the planes.
- In addition to keeping the filter components for the USB\_PLLVDD as close as practical to the body of the processor as previously mentioned, special care should be taken to avoid coupling switching power supply noise or digital switching noise onto the portion of that supply between the filter and the processor.
- The capacitors for C2 in the table below should be rated X5R or better due to temperature performance.

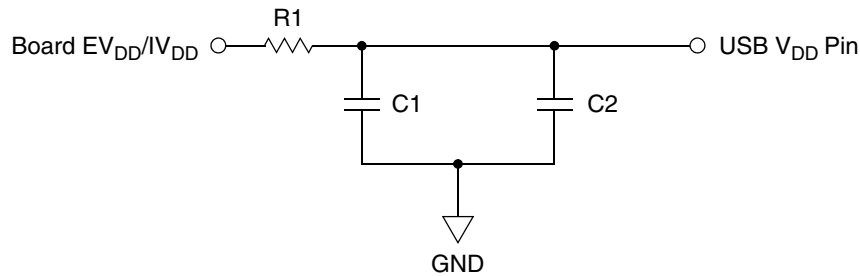


Figure 6. USB  $V_{DD}$  Power Filter

### NOTE

In addition to the above filter circuitry, a 0.01 F capacitor is also recommended in parallel with those shown.

Table 5 lists the resistor values and supply voltages to be used in the circuit for each of the USB  $V_{DD}$  pins.

Table 5. USB Filter Circuit Values

| USB $V_{DD}$ Pin                          | Nominal Voltage | R1 ( $\Omega$ ) | C1 ( $\mu$ F) | C2 ( $\mu$ F) |
|-------------------------------------------|-----------------|-----------------|---------------|---------------|
| USBVDD<br>(Bias generator supply)         | 3.3V            | 10              | 10            | 0.1           |
| USB_PHYVDD<br>(Main transceiver supply)   | 3.3V            | 0               | 10            | 0.1           |
| USB_PLLVDD<br>(PLL supply)                | 1.5V            | 10              | 1             | 0.1           |
| USB_OSCVDD<br>(Oscillator supply)         | 3.3V            | 0               | 10            | 0.1           |
| USB_OSCAVDD<br>(Oscillator analog supply) | 1.5V            | 0               | 10            | 0.1           |

## 4.4.1 Bias Resistor

The USBRBIAS resistor should be placed as close to the dedicated USB 2.0 pins as possible. The tolerance should be  $\pm 1\%$ .

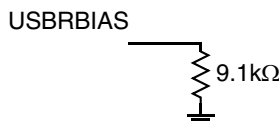


Figure 7. USBRBIAS Connection

## 5 Output Driver Capability and Loading

Table 6 lists values for drive capability and output loading.

Table 6. I/O Driver Capability<sup>1</sup>

| Signal                                                                                                                                          | Drive Capability | Output Load ( $C_L$ ) |
|-------------------------------------------------------------------------------------------------------------------------------------------------|------------------|-----------------------|
| SDRAMC (SDADDR[12:0], SDDATA[31:0], $\overline{RAS}$ , $\overline{CAS}$ , SDDM[3:0], $\overline{SDWE}$ , SDBA[1:0])                             | 24 mA            | 15 pF                 |
| SDRAMC DQS and clocks (SDDQS[3:0], SDRDQS, SDCLK[1:0], $\overline{SDCLK}$ [1:0], SDCKE)                                                         | 24 mA            | 15 pF                 |
| SDRAMC chip selects ( $\overline{SDCS}$ [3:0])                                                                                                  | 24 mA            | 15 pF                 |
| FlexBus (AD[31:0], $\overline{FBCS}$ [5:0], ALE, $\overline{R/W}$ , $\overline{BE/BWE}$ [3:0], $\overline{OE}$ )                                | 16 mA            | 30 pF                 |
| FEC ( $\overline{EnMDIO}$ , $\overline{EnMDC}$ , $\overline{EnTXEN}$ , $\overline{EnTXD}$ [3:0], $\overline{EnTXER}$ )                          | 8 mA             | 15 pF                 |
| Timer (TOUT[3:0])                                                                                                                               | 8 mA             | 50 pF                 |
| $\overline{DACK}$ [1:0]                                                                                                                         | 8 mA             | 30 pF                 |
| PSC ( $\overline{PSCnTXD}$ [3:0], $\overline{PSCnRTS}/\overline{PSCnFSYNC}$ ,                                                                   | 8 mA             | 30 pF                 |
| DSPI (DSPISOUT, DSPICS0/SS, DSPICS[2:3], DSPICS5/PCSS)                                                                                          | 24 mA            | 50 pF                 |
| PCI (PCIAD[31:0], PCIBG[4:1], PCIBG0/PCIREQOUT, PCIDEVSEL, PCICXBE[3:0], PCIFRM, PCIPERR, PCIRESET, PCISERR, PCISTOP, PCIPAR, PCITRDY, PCIIRDY) | 16 mA            | 50 pF                 |
| I2C (SCL, SDA)                                                                                                                                  | 8 mA             | 50 pF                 |
| BDM (PSTCLK, PSTDDATA[7:0], DSO/TDO,                                                                                                            | 8 mA             | 25 pF                 |
| RSTO                                                                                                                                            | 8 mA             | 50 pF                 |

<sup>1</sup> The device's pads have balanced sink and source current. The drive capability is the same as the sink capability.

# 6 PLL Timing Specifications

The specifications in Table 7 are for the CLKIN pin.

Table 7. Clock Timing Specifications

| Num | Characteristic                       | Min  | Max | Units |
|-----|--------------------------------------|------|-----|-------|
| C1  | Cycle time                           | 15.0 | 40  | ns    |
| C2  | Rise time (20% of Vdd to 80% of vdd) | —    | 2   | ns    |
| C3  | Fall time (80% of Vdd to 20% of Vdd) | —    | 2   | ns    |
| C4  | Duty cycle (at 50% of Vdd)           | 40   | 60  | %     |

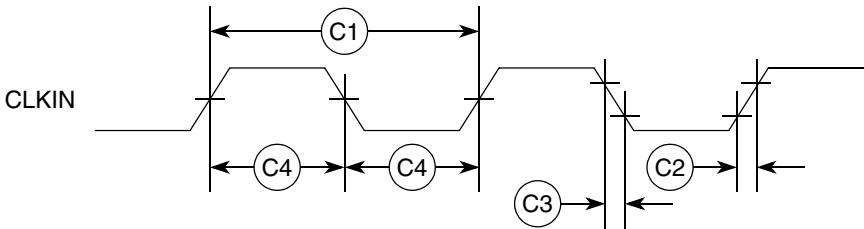


Figure 8. Input Clock Timing Diagram

Table 8 shows the supported PLL encodings.

Table 8. MCF547x Divide Ratio Encodings

| AD[12:8] <sup>1</sup> | Clock Ratio | CLKIN—PCI and FlexBus Frequency Range (MHz) | Internal XLB, SDRAM Bus, and PSTCLK Frequency Range (MHz) | Core Frequency Range (MHz) |
|-----------------------|-------------|---------------------------------------------|-----------------------------------------------------------|----------------------------|
| 00011                 | 1:2         | 41.67–66.66                                 | 83.33–133.33                                              | 166.66–266.66              |
| 00101                 | 1:2         | 25.0–44.42                                  | 50.0–88.83 <sup>2</sup>                                   | 100.0–177.66               |
| 01111                 | 1:4         | 25.0–33.3                                   | 100–133.33                                                | 200–266.66                 |

<sup>1</sup> All other values of AD[12:8] are reserved.

<sup>2</sup> DDR memories typically have a minimum speed of 83 MHz. Some vendors specify down to 75 MHz. Check with the memory component specifications to verify.

Figure 9 correlates CLKIN, internal bus, and core clock frequencies for the 1x–4x multipliers.

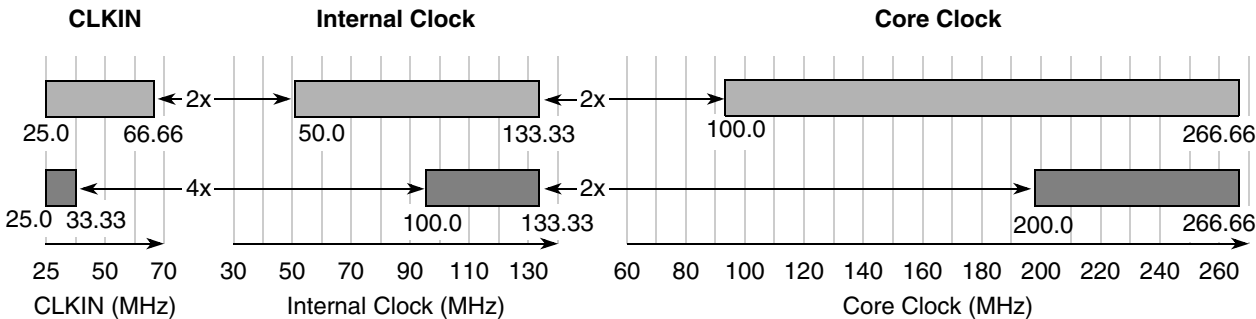


Figure 9. CLKIN, Internal Bus, and Core Clock Ratios

## 7 Reset Timing Specifications

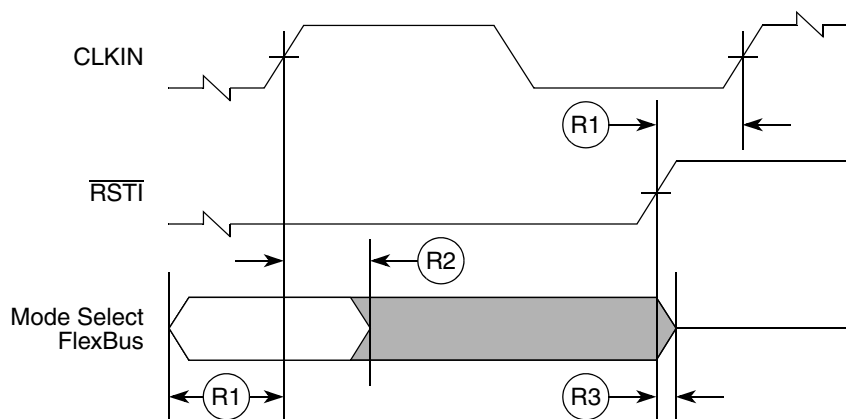
Table 9 lists specifications for the reset timing parameters shown in Figure 10

Table 9. Reset Timing Specifications

| Num             | Characteristic                             | 66 MHz CLKIN |     | Units        |
|-----------------|--------------------------------------------|--------------|-----|--------------|
|                 |                                            | Min          | Max |              |
| R1 <sup>1</sup> | Valid to CLKIN (setup)                     | 8            | —   | ns           |
| R2              | CLKIN to invalid (hold)                    | 1.0          | —   | ns           |
| R3              | $\overline{\text{RSTI}}$ to invalid (hold) | 1.0          | —   | ns           |
|                 | $\overline{\text{RSTI}}$ pulse duration    | 5            | —   | CLKIN cycles |

<sup>1</sup>  $\overline{\text{RSTI}}$  and FlexBus data lines are synchronized internally. Setup and hold times must be met only if recognition on a particular clock is required.

Figure 10 shows reset timing for the values in Table 9.



NOTE:

Mode selects are registered on the rising clock edge before the cycle in which  $\overline{\text{RSTI}}$  is recognized as being negated.

Figure 10. Reset Timing

## 8 FlexBus

A multi-function external bus interface called FlexBus is provided on the MCF5472 with basic functionality to interface to slave-only devices up to a maximum bus frequency of 66 MHz. It can be directly connected to asynchronous or synchronous devices such as external boot ROMs, flash memories, gate-array logic, or other simple target (slave) devices with little or no additional circuitry. For asynchronous devices, a simple chip-select based interface can be used. The FlexBus interface has six general purpose chip-selects ( $\overline{\text{FBCS}}[5:0]$ ). Chip-select  $\overline{\text{FBCS0}}$  can be dedicated to boot ROM access and can be programmed to be byte (8 bits), word (16 bits), or longword (32 bits) wide. Control signal timing is compatible with common ROM / flash memories.

## 8.1 FlexBus AC Timing Characteristics

The following timing numbers indicate when data is latched or driven onto the external bus, relative to the system clock.

**Table 10. FlexBus AC Timing Specifications**

| Num | Characteristic                                                                                                                                                                                           | Min   | Max | Unit | Notes           |
|-----|----------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|-------|-----|------|-----------------|
|     | Frequency of Operation                                                                                                                                                                                   | 25    | 66  | Mhz  | <sup>1</sup>    |
| FB1 | Clock Period (CLKIN)                                                                                                                                                                                     | 15.15 | 40  | ns   | <sup>2</sup>    |
| FB2 | Address, Data, and Control Output Valid (AD[31:0], $\overline{\text{FBCS}}[5:0]$ , R/W, ALE, TSIZ[1:0], $\overline{\text{BE}}/\text{BWE}[3:0]$ , $\overline{\text{OE}}$ , and $\overline{\text{TBST}}$ ) | —     | 7.0 | ns   | <sup>3</sup>    |
| FB3 | Address, Data, and Control Output Hold ((AD[31:0], $\overline{\text{FBCS}}[5:0]$ , R/W, ALE, TSIZ[1:0], $\overline{\text{BE}}/\text{BWE}[3:0]$ , $\overline{\text{OE}}$ , and $\overline{\text{TBST}}$ ) | 1     | —   | ns   | <sup>3, 4</sup> |
| FB4 | Data Input Setup                                                                                                                                                                                         | 3.5   | —   | ns   |                 |
| FB5 | Data Input Hold                                                                                                                                                                                          | 0     | —   | ns   |                 |
| FB6 | Transfer Acknowledge ( $\overline{\text{TA}}$ ) Input Setup                                                                                                                                              | 4     | —   | ns   |                 |
| FB7 | Transfer Acknowledge ( $\overline{\text{TA}}$ ) Input Hold                                                                                                                                               | 0     | —   | ns   |                 |
| FB8 | Address Output Valid (PCIAD[31:0])                                                                                                                                                                       | —     | 7.0 | ns   | <sup>5</sup>    |
| FB9 | Address Output Hold (PCIAD[31:0])                                                                                                                                                                        | 0     | —   | ns   | <sup>5</sup>    |

<sup>1</sup> The frequency of operation is the same as the PCI frequency of operation. The MCF547X supports a single external reference clock (CLKIN). This signal defines the frequency of operation for FlexBus and PCI.

<sup>2</sup> Max cycle rate is determined by CLKIN and how the user has the system PLL configured.

<sup>3</sup> Timing for chip selects only applies to the  $\overline{\text{FBCS}}[5:0]$  signals. Please see [Section 9.2, “DDR SDRAM AC Timing Characteristics”](#) for SDCS[3:0] timing.

<sup>4</sup> The FlexBus supports programming an extension of the address hold. Please consult the MCF547X specification manual for more information.

<sup>5</sup> These specs are used when the PCIAD[31:0] signals are configured as 32-bit, non-muxed FlexBus address signals.

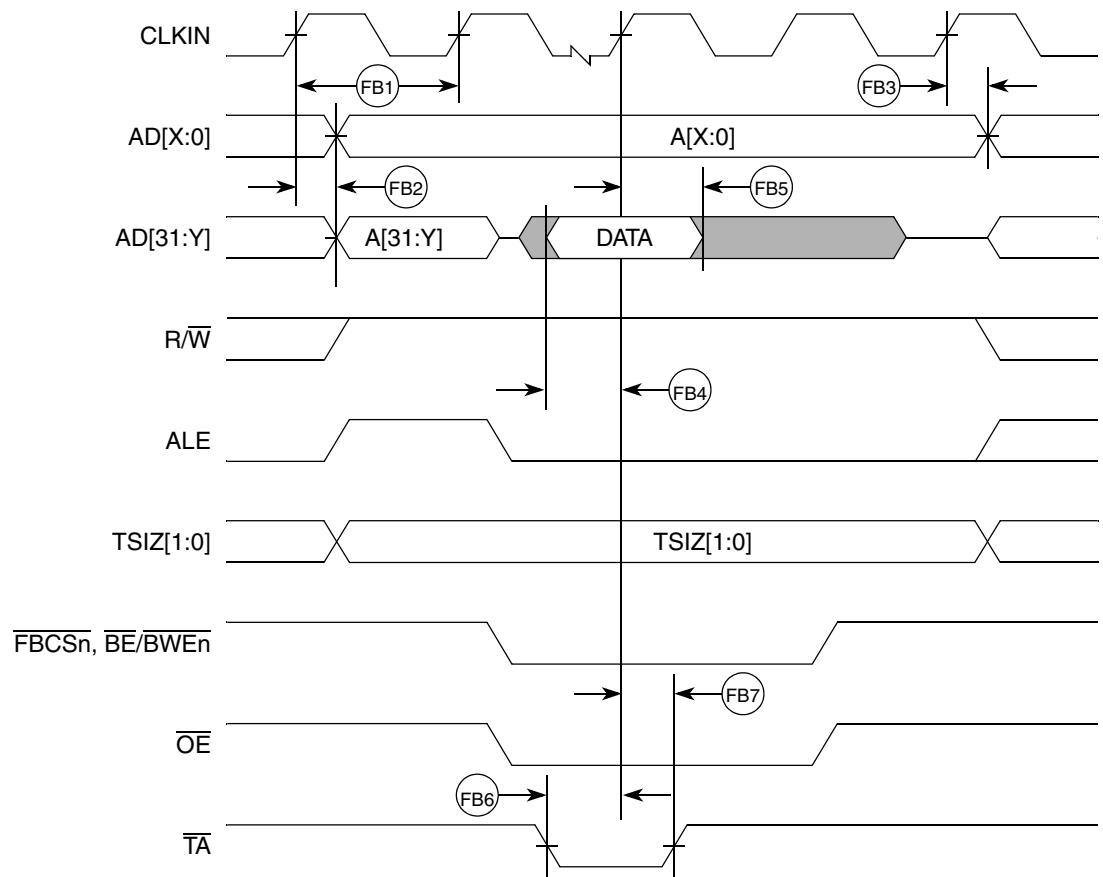


Figure 11. FlexBus Read Timing

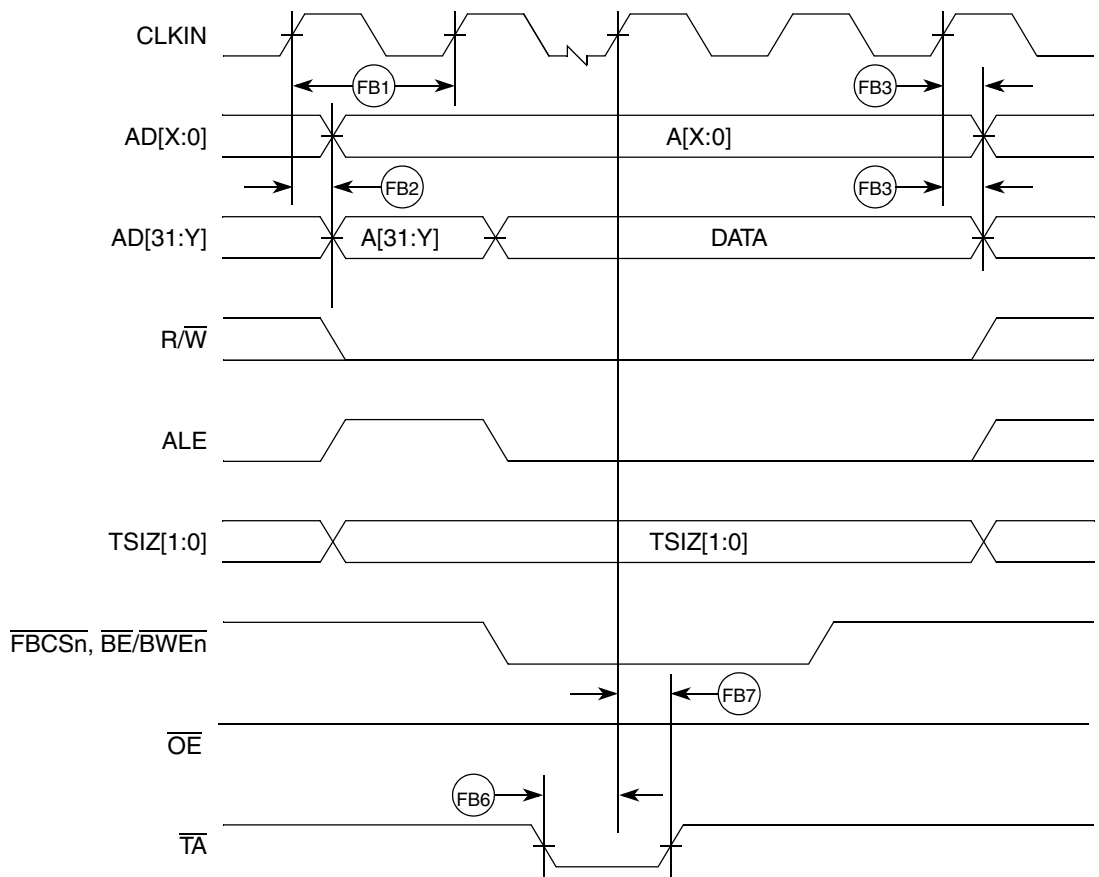


Figure 12. FlexBus Write Timing

## 9 SDRAM Bus

The SDRAM controller supports accesses to main SDRAM memory from any internal master. It supports standard SDRAM or double data rate (DDR) SDRAM, but it does not support both at the same time. The SDRAM controller uses SSTL2 and SSTL3 I/O drivers. Both SSTL drive modes are programmable for Class I or Class II drive strength.

### 9.1 SDR SDRAM AC Timing Characteristics

The following timing numbers indicate when data is latched or driven onto the external bus, relative to the memory bus clock, when operating in SDR mode on write cycles and relative to SDR\_DQS on read cycles. The MCF547x SDRAM controller is a DDR controller that has an SDR mode. Because it is designed to support DDR, a DQS pulse must be supplied to the MCF547x for each data beat of an SDR read. The MCF547x accomplishes this by asserting a signal called SDR\_DQS during read cycles. Care must be taken during board design to adhere to the following guidelines and specs with regard to the SDR\_DQS signal and its usage.

Table 11. SDR Timing Specifications

| Symbol | Characteristic                                                    | Min                                    | Max                                         | Unit  | Notes |
|--------|-------------------------------------------------------------------|----------------------------------------|---------------------------------------------|-------|-------|
|        | Frequency of Operation                                            | 0                                      | 133                                         | Mhz   | 1     |
| SD1    | Clock Period ( $t_{CK}$ )                                         | 7.52                                   | 12                                          | ns    | 2     |
| SD2    | Clock Skew ( $t_{SK}$ )                                           |                                        | TBD                                         |       |       |
| SD3    | Pulse Width High ( $t_{CKH}$ )                                    | 0.45                                   | 0.55                                        | SDCLK | 3     |
| SD4    | Pulse Width Low ( $t_{CKL}$ )                                     | 0.45                                   | 0.55                                        | SDCLK | 4     |
| SD5    | Address, CKE, CAS, RAS, WE, BA, CS - Output Valid ( $t_{CMV}$ )   |                                        | $0.5 \times \text{SDCLK} + 1.0\text{ns}$    | ns    |       |
| SD6    | Address, CKE, CAS, RAS, WE, BA, CS - Output Hold ( $t_{CMH}$ )    | 2.0                                    |                                             | ns    |       |
| SD7    | SDRDQS Output Valid ( $t_{DQSOV}$ )                               |                                        | Self timed                                  | ns    | 5     |
| SD8    | SDDQS[3:0] input setup relative to SDCLK ( $t_{DQSI S}$ )         | $0.25 \times \text{SDCLK}$             | $0.40 \times \text{SDCLK}$                  | ns    | 6     |
| SD9    | SDDQS[3:0] input hold relative to SDCLK ( $t_{DQSIH}$ )           | Does not apply. 0.5 SDCLK fixed width. |                                             |       | 7     |
| SD10   | Data Input Setup relative to SDCLK (reference only) ( $t_{DIS}$ ) | $0.25 \times \text{SDCLK}$             |                                             | ns    | 8     |
| SD11   | Data Input Hold relative to SDCLK (reference only) ( $t_{DIH}$ )  | 1.0                                    |                                             | ns    |       |
| SD12   | Data and Data Mask Output Valid ( $t_{DV}$ )                      |                                        | $0.75 \times \text{SDCLK} + 0.500\text{ns}$ | ns    |       |
| SD13   | Data and Data Mask Output Hold ( $t_{DH}$ )                       | 1.5                                    |                                             | ns    |       |

<sup>1</sup> The frequency of operation is 2x or 4x the CLKIN frequency of operation. The MCF547X supports a single external reference clock (CLKIN). This signal defines the frequency of operation for FlexBus and PCI, but SDRAM clock operates at the same frequency as the internal bus clock. Please see the PLL chapter of the *MCF547X Reference Manual* for more information on setting the SDRAM clock rate.

<sup>2</sup> SDCLK is one SDRAM clock in (ns).

<sup>3</sup> Pulse width high plus pulse width low cannot exceed min and max clock period.

<sup>4</sup> Pulse width high plus pulse width low cannot exceed min and max clock period.

<sup>5</sup> SDR\_DQS is designed to pulse 0.25 clock before the rising edge of the memory clock. This is a guideline only. Subtle variation from this guideline is expected. SDR\_DQS only pulses during a read cycle and one pulse occurs for each data beat.

<sup>6</sup> SDR\_DQS is designed to pulse 0.25 clock before the rising edge of the memory clock. This spec is a guideline only. Subtle variation from this guideline is expected. SDR\_DQS only pulses during a read cycle and one pulse occurs for each data beat.

<sup>7</sup> The SDR\_DQS pulse is designed to be 0.5 clock in width. The timing of the rising edge is most important. The falling edge does not affect the memory controller.

<sup>8</sup> Because a read cycle in SDR mode uses the DQS circuit within the MCF547X, it is most critical that the data valid window be centered 1/4 clk after the rising edge of DQS. Ensuring that this happens results in successful SDR reads. The input setup spec is provided as guidance.

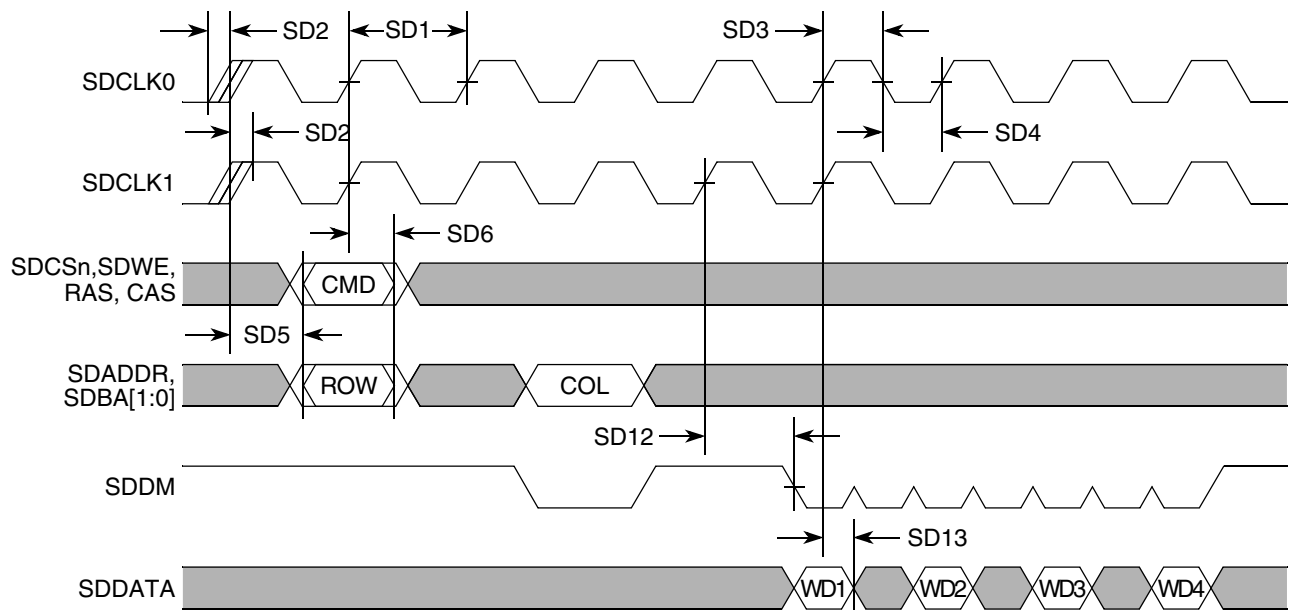


Figure 13. SDR Write Timing

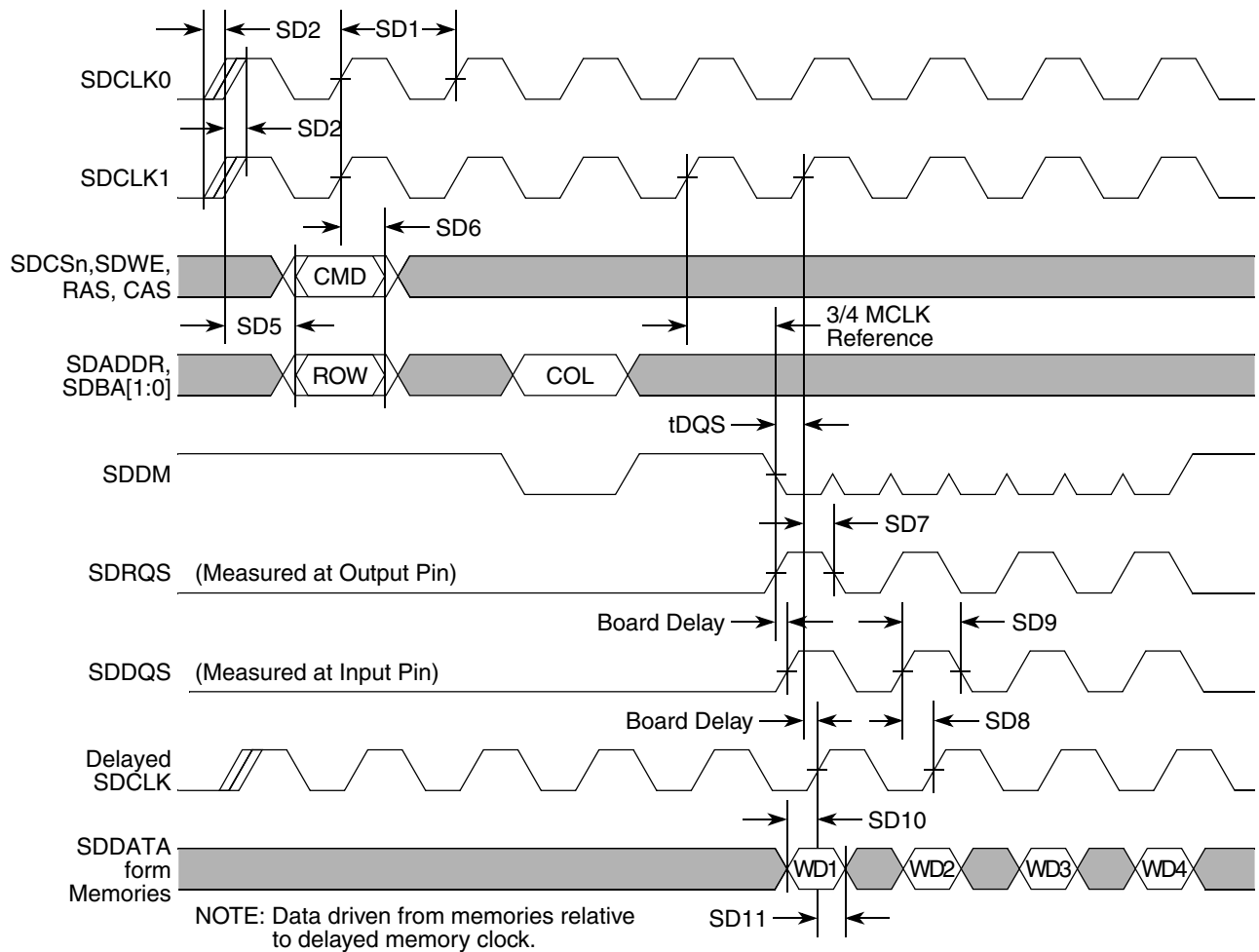


Figure 14. SDR Read Timing

## 9.2 DDR SDRAM AC Timing Characteristics

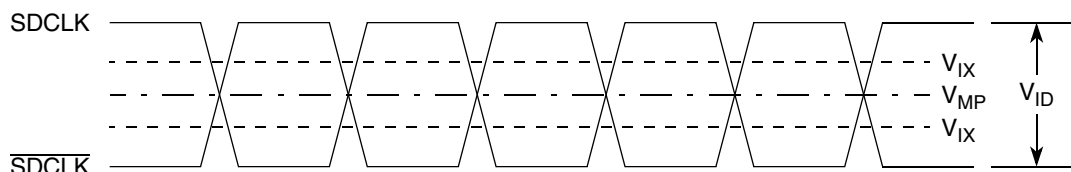
When using the DDR SDRAM controller, the following timing numbers must be followed to properly latch or drive data onto the memory bus. All timing numbers are relative to the four DQS byte lanes.

Table 12 shows the DDR clock crossover specifications.

**Table 12. DDR Clock Crossover Specifications**

| Symbol    | Characteristic                                         | Min  | Max          | Unit |
|-----------|--------------------------------------------------------|------|--------------|------|
| $V_{MP}$  | Clock output mid-point voltage                         | 1.05 | 1.45         | V    |
| $V_{OUT}$ | Clock output voltage level                             | -0.3 | SD_VDD + 0.3 | V    |
| $V_{ID}$  | Clock output differential voltage (peak to peak swing) | 0.7  | SD_VDD + 0.6 | V    |
| $V_{IX}$  | Clock crossing point voltage <sup>1</sup>              | 1.05 | 1.45         | V    |

<sup>1</sup> The clock crossover voltage is only guaranteed when using the highest drive strength option for the SDCLK[1:0] and SDCLK[1:0] signals.



**Figure 15. DDR Clock Timing Diagram**

**Table 13. DDR Timing Specifications**

| Symbol | Characteristic                                                                                                              | Min                                         | Max                                        | Unit  | Notes                        |
|--------|-----------------------------------------------------------------------------------------------------------------------------|---------------------------------------------|--------------------------------------------|-------|------------------------------|
|        | Frequency of Operation                                                                                                      | 50 <sup>1</sup>                             | 133                                        | MHz   | <sup>2</sup>                 |
| DD1    | Clock Period ( $t_{CK}$ )                                                                                                   | 7.52                                        | 12                                         | ns    | <sup>3</sup>                 |
| DD2    | Pulse Width High ( $t_{CKH}$ )                                                                                              | 0.45                                        | 0.55                                       | SDCLK | <sup>4</sup>                 |
| DD3    | Pulse Width Low ( $t_{CKL}$ )                                                                                               | 0.45                                        | 0.55                                       | SDCLK | <sup>5</sup>                 |
| DD4    | Address, SDCKE, $\overline{CAS}$ , $\overline{RAS}$ , $\overline{WE}$ , SDBA, $\overline{SDCS}$ —Output Valid ( $t_{CMV}$ ) | —                                           | $0.5 \times \text{SDCLK} + 1.0 \text{ ns}$ | ns    | <sup>6</sup>                 |
| DD5    | Address, SDCKE, $\overline{CAS}$ , $\overline{RAS}$ , $\overline{WE}$ , SDBA, $\overline{SDCS}$ —Output Hold ( $t_{CMH}$ )  | 2.0                                         | —                                          | ns    |                              |
| DD6    | Write Command to first DQS Latching Transition ( $t_{DQSS}$ )                                                               | —                                           | 1.25                                       | SDCLK |                              |
| DD7    | Data and Data Mask Output Setup (DQ→DQS) Relative to DQS (DDR Write Mode) ( $t_{QS}$ )                                      | 1.0                                         | —                                          | ns    | <sup>7</sup><br><sup>8</sup> |
| DD8    | Data and Data Mask Output Hold (DQS→DQ) Relative to DQS (DDR Write Mode) ( $t_{QH}$ )                                       | 1.0                                         | —                                          | ns    | <sup>9</sup>                 |
| DD9    | Input Data Skew Relative to DQS (Input Setup) ( $t_{IS}$ )                                                                  |                                             | 1                                          | ns    | <sup>10</sup>                |
| DD10   | Input Data Hold Relative to DQS ( $t_{IH}$ )                                                                                | $0.25 \times \text{SDCLK} + 0.5 \text{ ns}$ | —                                          | ns    | <sup>11</sup>                |
| DD11   | DQS falling edge to SDCLK rising (output setup time) ( $t_{DSS}$ )                                                          | 0.5                                         | —                                          | ns    |                              |
| DD12   | DQS falling edge from SDCLK rising (output hold time) ( $t_{DSH}$ )                                                         | 0.5                                         | —                                          | ns    |                              |

Table 13. DDR Timing Specifications (continued)

| Symbol | Characteristic                                  | Min  | Max | Unit  | Notes |
|--------|-------------------------------------------------|------|-----|-------|-------|
| DD13   | DQS input read preamble width ( $t_{RPRE}$ )    | 0.9  | 1.1 | SDCLK |       |
| DD14   | DQS input read postamble width ( $t_{RPST}$ )   | 0.4  | 0.6 | SDCLK |       |
| DD15   | DQS output write preamble width ( $t_{WPRE}$ )  | 0.25 | —   | SDCLK |       |
| DD16   | DQS output write postamble width ( $t_{WPST}$ ) | 0.4  | 0.6 | SDCLK |       |

<sup>1</sup> DDR memories typically have a minimum speed specification of 83 MHz. Check memory component specifications to verify.

<sup>2</sup> The frequency of operation is 2x or 4x the CLKIN frequency of operation. The MCF547X supports a single external reference clock (CLKIN). This signal defines the frequency of operation for FlexBus and PCI, but SDRAM clock operates at the same frequency as the internal bus clock. Please see the reset configuration signals description in the “Signal Descriptions” chapter within the *MCF547x Reference Manual*.

<sup>3</sup> SDCLK is one memory clock in (ns).

<sup>4</sup> Pulse width high plus pulse width low cannot exceed max clock period.

<sup>5</sup> Pulse width high plus pulse width low cannot exceed max clock period.

<sup>6</sup> Command output valid should be 1/2 the memory bus clock (SDCLK) plus some minor adjustments for process, temperature, and voltage variations.

<sup>7</sup> This specification relates to the required input setup time of today's DDR memories. SDDATA[31:24] is relative to SDDQS3, SDDATA[23:16] is relative to SDDQS2, SDDATA[15:8] is relative to SDDQS1, and SDDATA[7:0] is relative SDDQS0.

<sup>8</sup> The first data beat is valid before the first rising edge of SDDQS and after the SDDQS write preamble. The remaining data beats is valid for each subsequent SDDQS edge.

<sup>9</sup> This specification relates to the required hold time of today's DDR memories. SDDATA[31:24] is relative to SDDQS3, SDDATA[23:16] is relative to SDDQS2, SDDATA[15:8] is relative to SDDQS1, and SDDATA[7:0] is relative SDDQS0.

<sup>10</sup> Data input skew is derived from each SDDQS clock edge. It begins with a SDDQS transition and ends when the last data line becomes valid. This input skew must include DDR memory output skew and system level board skew (due to routing or other factors).

<sup>11</sup> Data input hold is derived from each SDDQS clock edge. It begins with a SDDQS transition and ends when the first data line becomes invalid.

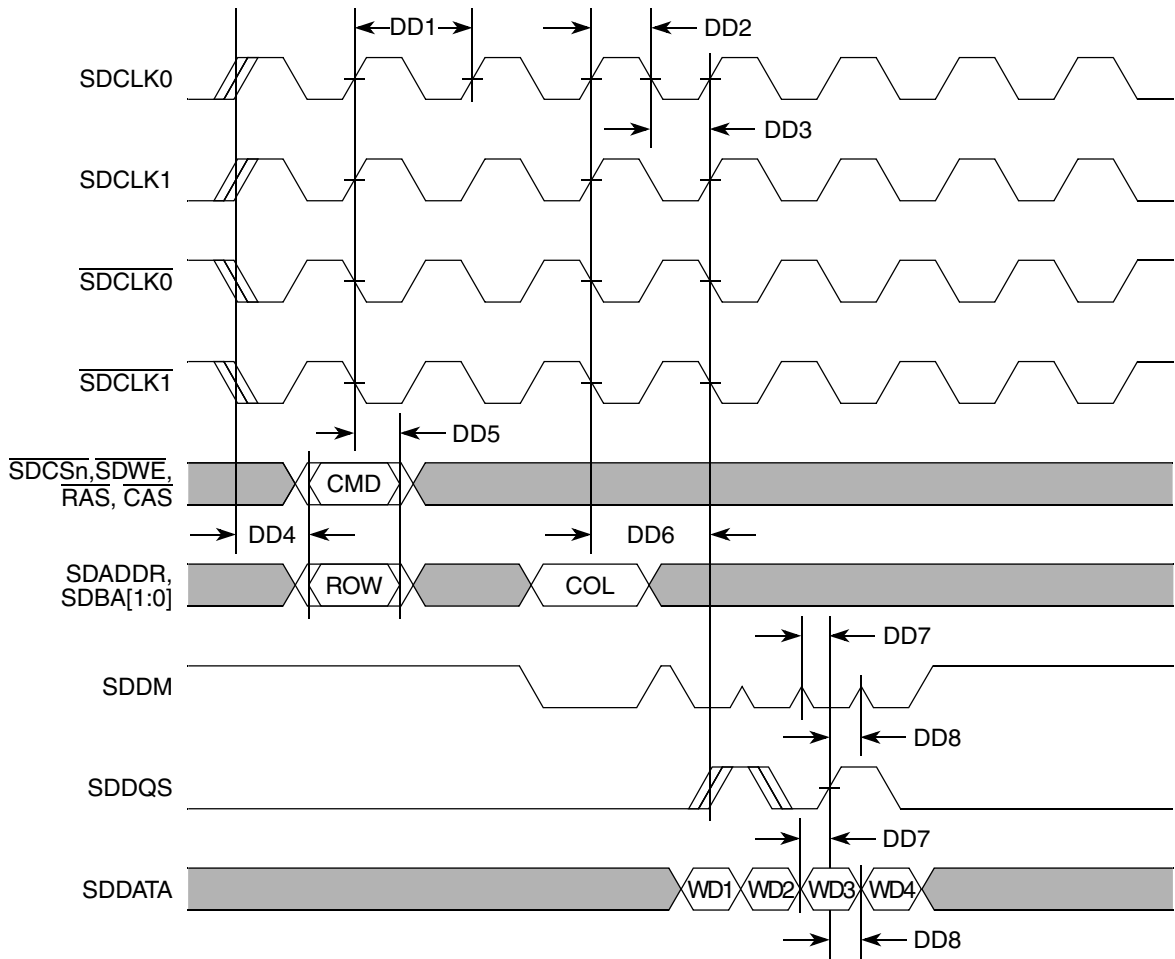


Figure 16. DDR Write Timing

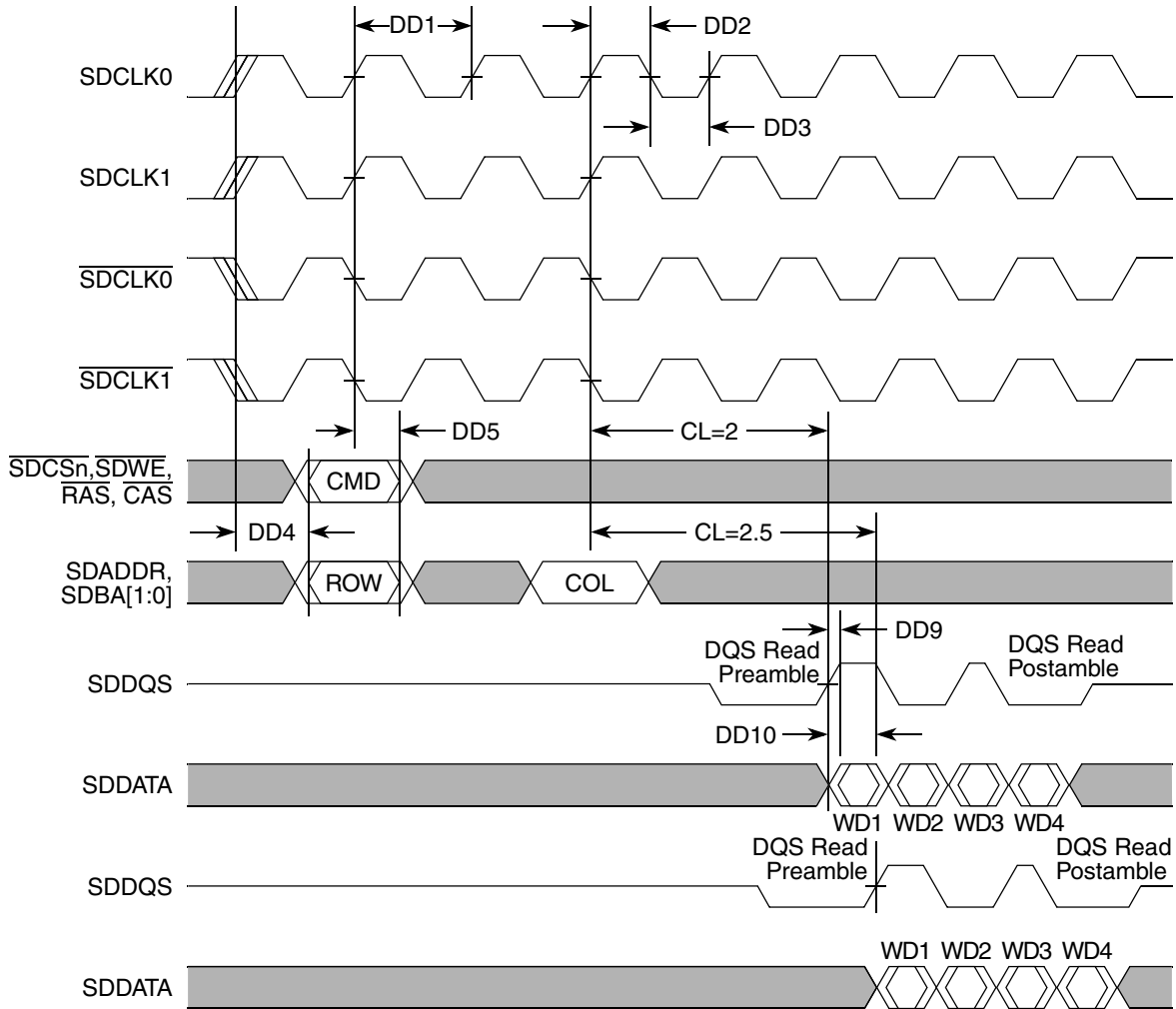


Figure 17. DDR Read Timing

# 10 PCI Bus

The PCI bus on the MCF547x is PCI 2.2 compliant. The following timing numbers are mostly from the PCI 2.2 spec. Please refer to the PCI 2.2 spec for a more detailed timing analysis.

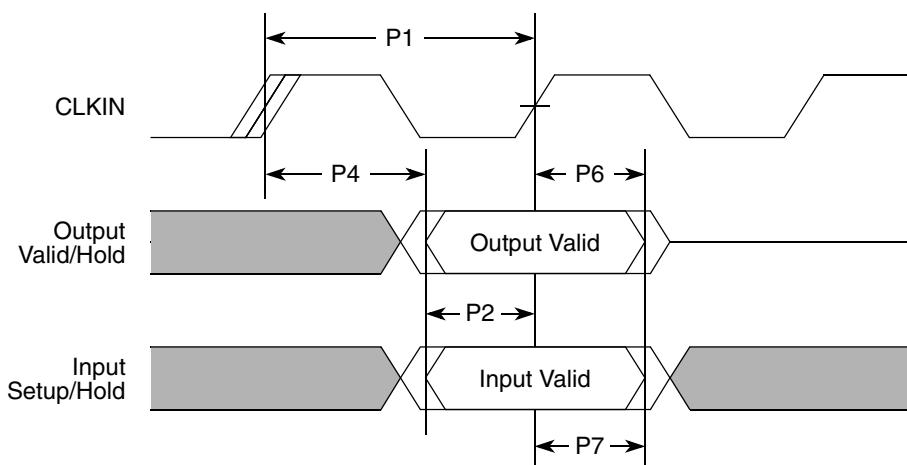
Table 14. PCI Timing Specifications

| Num | Characteristic                                                                                | Min   | Max  | Unit | Notes        |
|-----|-----------------------------------------------------------------------------------------------|-------|------|------|--------------|
|     | Frequency of Operation                                                                        | 25    | 66   | MHz  | <sup>1</sup> |
| P1  | Clock Period ( $t_{CK}$ )                                                                     | 15.15 | 40   | ns   | <sup>2</sup> |
| P2  | Address, Data, and Command ( $33 < \text{PCI} \leq 66 \text{ Mhz}$ )—Input Setup ( $t_{IS}$ ) | 3.0   | —    | ns   |              |
| P3  | Address, Data, and Command ( $0 < \text{PCI} \leq 33 \text{ Mhz}$ )—Input Setup ( $t_{IS}$ )  | 7.0   | —    | ns   |              |
| P4  | Address, Data, and Command ( $33\text{--}66 \text{ Mhz}$ )—Output Valid ( $t_{DV}$ )          | —     | 6.0  | ns   | <sup>3</sup> |
| P5  | Address, Data, and Command ( $0\text{--}33 \text{ Mhz}$ ) - Output Valid ( $t_{DV}$ )         | —     | 11.0 | ns   |              |
| P6  | PCI signals ( $0\text{--}66 \text{ Mhz}$ ) - Output Hold ( $t_{DH}$ )                         | 0     | —    | ns   | <sup>4</sup> |

**Table 14. PCI Timing Specifications (continued)**

| Num | Characteristic                                             | Min | Max | Unit | Notes        |
|-----|------------------------------------------------------------|-----|-----|------|--------------|
| P7  | PCI signals (0–66 Mhz) - Input Hold ( $t_{IH}$ )           | 0   | —   | ns   | <sup>5</sup> |
| P8  | PCI REQ/GNT (33 < PCI ≤ 66Mhz) - Output valid ( $t_{DV}$ ) | —   | 6   | ns   | <sup>6</sup> |
| P9  | PCI REQ/GNT (0 < PCI ≤ 33Mhz) - Output valid ( $t_{DV}$ )  | —   | 12  | ns   |              |
| P10 | PCI REQ/GNT (33 < PCI ≤ 66Mhz) - Input Setup ( $t_{IS}$ )  | —   | 5   | ns   |              |
| P11 | PCI REQ (0 < PCI ≤ 33Mhz) - Input Setup ( $t_{IS}$ )       | 12  | —   | ns   |              |
| P12 | PCI GNT (0 < PCI ≤ 33Mhz) - Input Setup ( $t_{IS}$ )       | 10  | —   | ns   |              |

- <sup>1</sup> Please see the reset configuration signals description in the “Signal Descriptions” chapter within the *MCF547x Reference Manual*. Also specific guidelines may need to be followed when operating the system PLL below certain frequencies.
- <sup>2</sup> Max cycle rate is determined by CLKIN and how the user has the system PLL configured.
- <sup>3</sup> All signals defined as PCI based signals. Does not include PTP (point-to-point) signals.
- <sup>4</sup> PCI 2.2 spec does not require an output hold time. Although the MCF547X may provide a slight amount of hold, it is not required or guaranteed.
- <sup>5</sup> PCI 2.2 spec requires zero input hold.
- <sup>6</sup> These signals are defined at PTP (Point-to-point) in the PCI 2.2 spec.



**Figure 18. PCI Timing**

## 11 Fast Ethernet AC Timing Specifications

### 11.1 MII/7-WIRE Interface Timing Specs

The following timing specs are defined at the chip I/O pin and must be translated appropriately to arrive at timing specs/constraints for the EMAC\_10\_100 I/O signals.

The following timing specs meet the requirements for MII and 7-Wire style interfaces for a range of transceiver devices. If this interface is to be used with a specific transceiver device the timing specs may be altered to match that specific transceiver.

Table 15. MII Receive Signal Timing

| Num | Characteristic                      | Min | Max | Unit         |
|-----|-------------------------------------|-----|-----|--------------|
| M1  | RXD[3:0], RXDV, RXER to RXCLK setup | 5   | —   | ns           |
| M2  | RXCLK to RXD[3:0], RXDV, RXER hold  | 5   | —   | ns           |
| M3  | RXCLK pulse width high              | 35% | 65% | RXCLK period |
| M4  | RXCLK pulse width low               | 35% | 65% | RXCLK period |

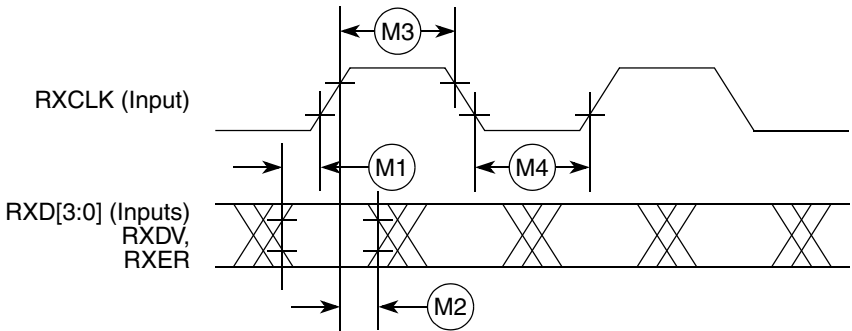


Figure 19. MII Receive Signal Timing Diagram

## 11.2 MII Transmit Signal Timing

Table 16. MII Transmit Signal Timing

| Num | Characteristic                        | Min | Max | Unit         |
|-----|---------------------------------------|-----|-----|--------------|
| M5  | TXCLK to TXD[3:0], TXEN, TXER invalid | 0   | —   | ns           |
| M6  | TXCLK to TXD[3:0], TXEN, TXER valid   | —   | 25  | ns           |
| M7  | TXCLK pulse width high                | 35% | 65% | TXCLK period |
| M8  | TXCLK pulse width low                 | 35% | 65% | TXCLK period |

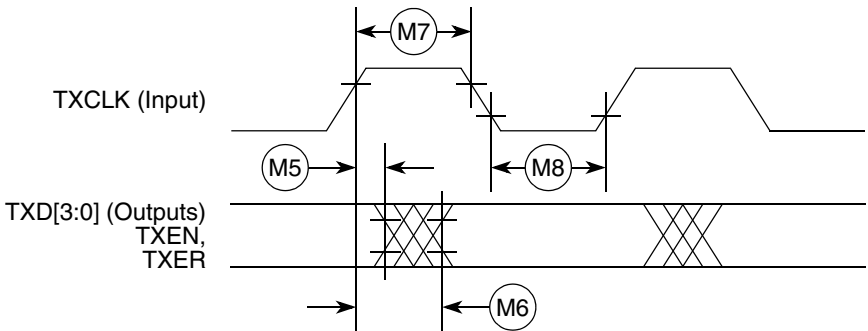


Figure 20. MII Transmit Signal Timing Diagram

## 11.3 MII Async Inputs Signal Timing (CRS, COL)

Table 17. MII Transmit Signal Timing

| Num | Characteristic               | Min | Max | Unit          |
|-----|------------------------------|-----|-----|---------------|
| M9  | CRS, COL minimum pulse width | 1.5 | —   | TX_CLK period |

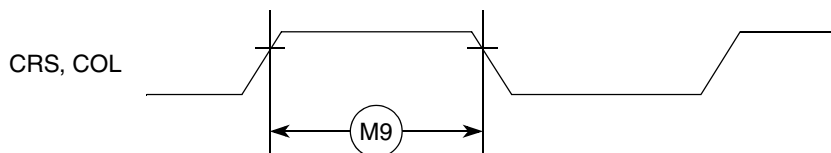


Figure 21. MII Async Inputs Timing Diagram

## 11.4 MII Serial Management Channel Timing (MDIO,MDC)

Table 18. MII Serial Management Channel Signal Timing

| Num | Characteristic                                           | Min | Max | Unit       |
|-----|----------------------------------------------------------|-----|-----|------------|
| M10 | MDC falling edge to MDIO output invalid (min prop delay) | 0   | —   | ns         |
| M11 | MDC falling edge to MDIO output valid (max prop delay)   | —   | 25  | ns         |
| M12 | MDIO (input) to MDC rising edge setup                    | 10  | —   | ns         |
| M13 | MDIO (input) to MDC rising edge hold                     | 0   | —   | ns         |
| M14 | MDC pulse width high                                     | 40% | 60% | MDC period |
| M15 | MDC pulse width low                                      | 40% | 60% | MDC period |

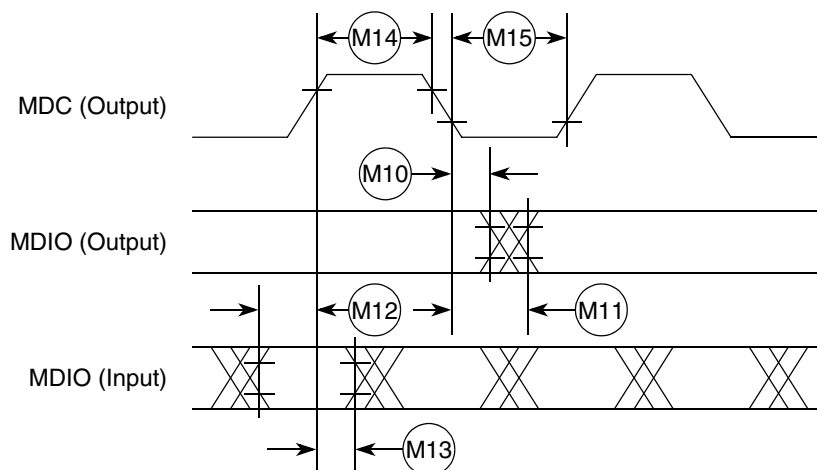


Figure 22. MII Serial Management Channel Timing Diagram

# 12 General Timing Specifications

Table 19 lists timing specifications for the GPIO, PSC,  $\overline{\text{DREQ}}$ ,  $\overline{\text{DACK}}$ , and external interrupts.

**Table 19. General AC Timing Specifications**

| Name | Characteristic                             | Min | Max | Unit   |
|------|--------------------------------------------|-----|-----|--------|
| G1   | CLKIN high to signal output valid          | —   | 2   | PSTCLK |
| G2   | CLKIN high to signal invalid (output hold) | 0   | —   | ns     |
| G3   | Signal input pulse width                   | 2   | —   | PSTCLK |

# 13 I<sup>2</sup>C Input/Output Timing Specifications

Table 20 lists specifications for the I<sup>2</sup>C input timing parameters shown in Figure 23.

**Table 20. I<sup>2</sup>C Input Timing Specifications between SCL and SDA**

| Num | Characteristic                                                             | Min | Max | Units      |
|-----|----------------------------------------------------------------------------|-----|-----|------------|
| I1  | Start condition hold time                                                  | 2   | —   | Bus clocks |
| I2  | Clock low period                                                           | 8   | —   | Bus clocks |
| I3  | SCL/SDA rise time ( $V_{IL} = 0.5 \text{ V}$ to $V_{IH} = 2.4 \text{ V}$ ) | —   | 1   | mS         |
| I4  | Data hold time                                                             | 0   | —   | ns         |
| I5  | SCL/SDA fall time ( $V_{IH} = 2.4 \text{ V}$ to $V_{IL} = 0.5 \text{ V}$ ) | —   | 1   | mS         |
| I6  | Clock high time                                                            | 4   | —   | Bus clocks |
| I7  | Data setup time                                                            | 0   | —   | ns         |
| I8  | Start condition setup time (for repeated start condition only)             | 2   | —   | Bus clocks |
| I9  | Stop condition setup time                                                  | 2   | —   | Bus clocks |

Table 21 lists specifications for the I<sup>2</sup>C output timing parameters shown in Figure 23.

**Table 21. I<sup>2</sup>C Output Timing Specifications between SCL and SDA**

| Num             | Characteristic                                                             | Min | Max | Units         |
|-----------------|----------------------------------------------------------------------------|-----|-----|---------------|
| I1 <sup>1</sup> | Start condition hold time                                                  | 6   | —   | Bus clocks    |
| I2 <sup>1</sup> | Clock low period                                                           | 10  | —   | Bus clocks    |
| I3 <sup>2</sup> | SCL/SDA rise time ( $V_{IL} = 0.5 \text{ V}$ to $V_{IH} = 2.4 \text{ V}$ ) | —   | —   | $\mu\text{S}$ |
| I4 <sup>1</sup> | Data hold time                                                             | 7   | —   | Bus clocks    |
| I5 <sup>3</sup> | SCL/SDA fall time ( $V_{IH} = 2.4 \text{ V}$ to $V_{IL} = 0.5 \text{ V}$ ) | —   | 3   | ns            |
| I6 <sup>1</sup> | Clock high time                                                            | 10  | —   | Bus clocks    |
| I7 <sup>1</sup> | Data setup time                                                            | 2   | —   | Bus clocks    |
| I8 <sup>1</sup> | Start condition setup time (for repeated start condition only)             | 20  | —   | Bus clocks    |
| I9 <sup>1</sup> | Stop condition setup time                                                  | 10  | —   | Bus clocks    |

- <sup>1</sup> Output numbers depend on the value programmed into the IFDR; an IFDR programmed with the maximum frequency (IFDR = 0x20) results in minimum output timings as shown in Table 21. The I<sup>2</sup>C interface is designed to scale the actual data transition time to move it to the middle of the SCL low period. The actual position is affected by the prescale and division values programmed into the IFDR; however, the numbers given in Table 21 are minimum values.
- <sup>2</sup> Because SCL and SDA are open-collector-type outputs, which the processor can only actively drive low, the time SCL or SDA take to reach a high level depends on external signal capacitance and pull-up resistor values.
- <sup>3</sup> Specified at a nominal 50-pF load.

Figure 23 shows timing for the values in Table 20 and Table 21.

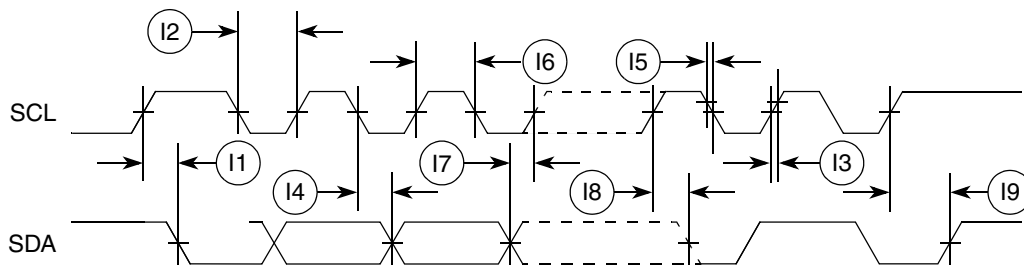


Figure 23. I<sup>2</sup>C Input/Output Timings

## 14 JTAG and Boundary Scan Timing

Table 22. JTAG and Boundary Scan Timing

| Num | Characteristics <sup>1</sup>                                | Symbol              | Min   | Max  | Unit            |
|-----|-------------------------------------------------------------|---------------------|-------|------|-----------------|
| J1  | TCLK Frequency of Operation                                 | f <sub>JCYC</sub>   | DC    | 10   | MHz             |
| J2  | TCLK Cycle Period                                           | t <sub>JCYC</sub>   | 2     | —    | t <sub>CK</sub> |
| J3  | TCLK Clock Pulse Width                                      | t <sub>JCW</sub>    | 15.15 | —    | ns              |
| J4  | TCLK Rise and Fall Times                                    | t <sub>JCRF</sub>   | 0.0   | 3.0  | ns              |
| J5  | Boundary Scan Input Data Setup Time to TCLK Rise            | t <sub>BSDST</sub>  | 5.0   | —    | ns              |
| J6  | Boundary Scan Input Data Hold Time after TCLK Rise          | t <sub>BSDHT</sub>  | 24.0  | —    | ns              |
| J7  | TCLK Low to Boundary Scan Output Data Valid                 | t <sub>BSDV</sub>   | 0.0   | 15.0 | ns              |
| J8  | TCLK Low to Boundary Scan Output High Z                     | t <sub>BSDZ</sub>   | 0.0   | 15.0 | ns              |
| J9  | TMS, TDI Input Data Setup Time to TCLK Rise                 | t <sub>TAPBST</sub> | 5.0   | —    | ns              |
| J10 | TMS, TDI Input Data Hold Time after TCLK Rise               | t <sub>TAPBHT</sub> | 10.0  | —    | ns              |
| J11 | TCLK Low to TDO Data Valid                                  | t <sub>TDODV</sub>  | 0.0   | 20.0 | ns              |
| J12 | TCLK Low to TDO High Z                                      | t <sub>TDODZ</sub>  | 0.0   | 15.0 | ns              |
| J13 | $\overline{\text{TRST}}$ Assert Time                        | t <sub>TRSTAT</sub> | 100.0 | —    | ns              |
| J14 | $\overline{\text{TRST}}$ Setup Time (Negation) to TCLK High | t <sub>TRSTST</sub> | 10.0  | —    | ns              |

<sup>1</sup> MTMOD is expected to be a static signal. Hence, it is not associated with any timing

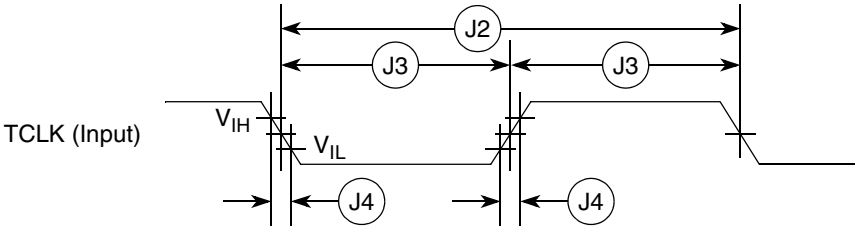


Figure 24. Test Clock Input Timing

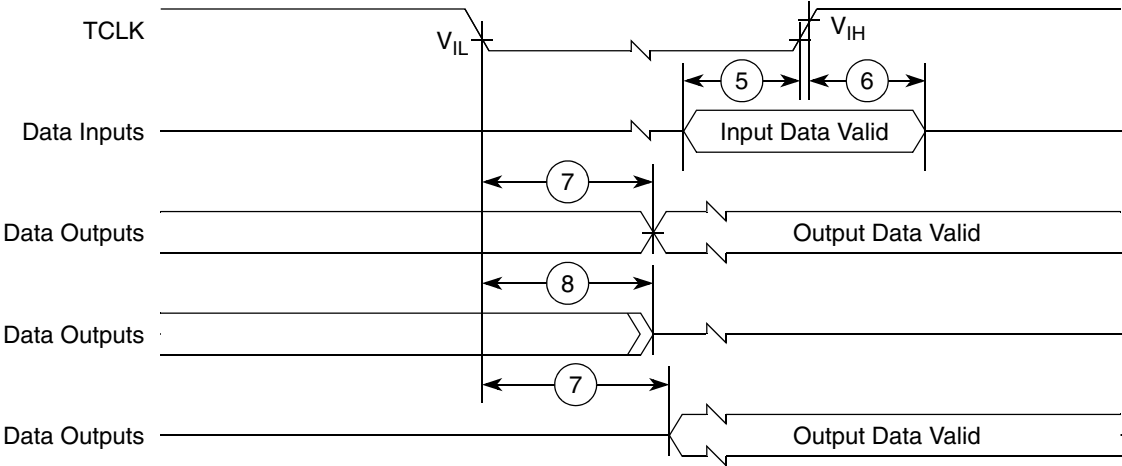


Figure 25. Boundary Scan (JTAG) Timing

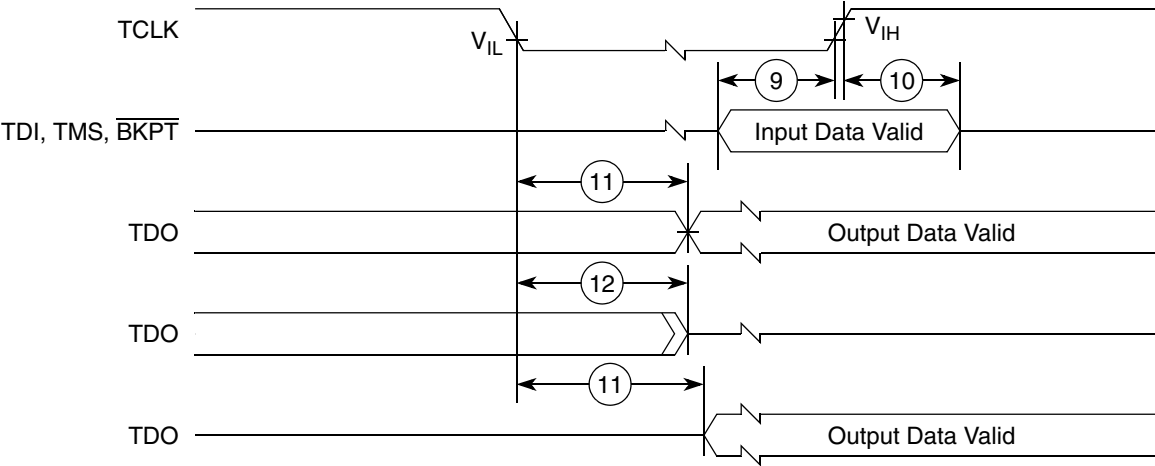


Figure 26. Test Access Port Timing

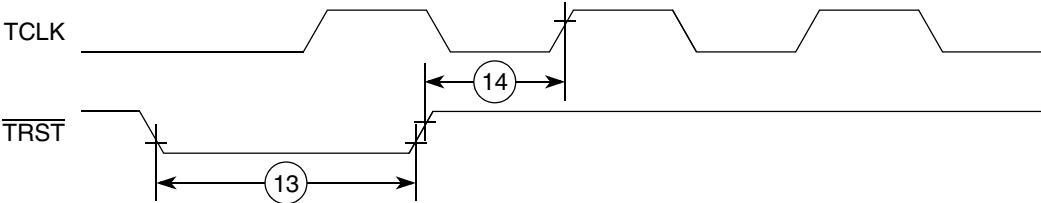


Figure 27. TRST Timing Debug AC Timing Specifications

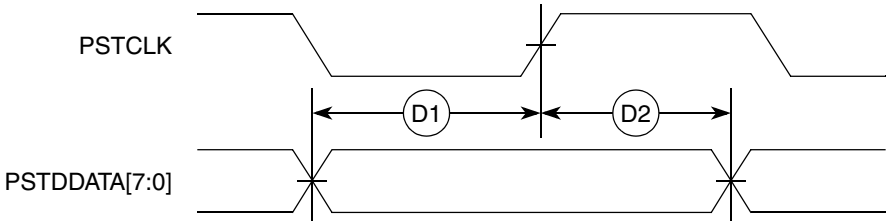
Table 23 lists specifications for the debug AC timing parameters shown in Figure 29.

**Table 23. Debug AC Timing Specifications**

| Num             | Characteristic           | 66 MHz |     | Units   |
|-----------------|--------------------------|--------|-----|---------|
|                 |                          | Min    | Max |         |
| D1              | PSTDDATA to PSTCLK setup | 4.5    | —   | ns      |
| D2              | PSTCLK to PSTDDATA hold  | 4.5    | —   | ns      |
| D3              | DSI-to-DSCLK setup       | 1      | —   | PSTCLKs |
| D4 <sup>1</sup> | DSCLK-to-DSO hold        | 4      | —   | PSTCLKs |
| D5              | DSCLK cycle time         | 5      | —   | PSTCLKs |

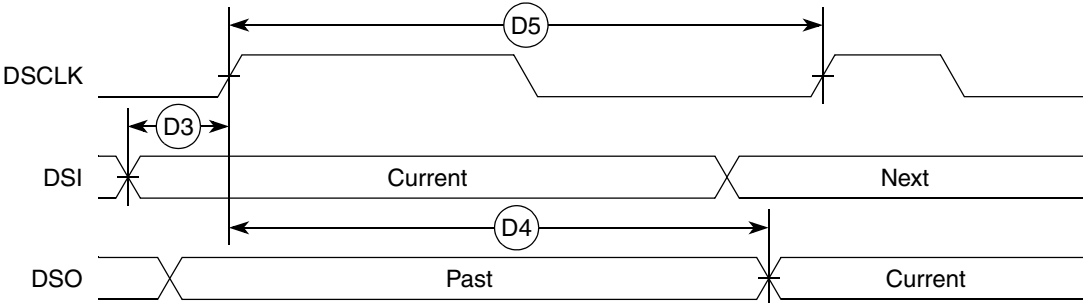
<sup>1</sup> DSCLK and DSI are synchronized internally. D4 is measured from the synchronized DSCLK input relative to the rising edge of CLKOUT.

Figure 28 shows real-time trace timing for the values in Table 23.



**Figure 28. Real-Time Trace AC Timing**

Figure 29 shows BDM serial port AC timing for the values in Table 23.



**Figure 29. BDM Serial Port AC Timing**

# 15 DSPI Electrical Specifications

Table 24 lists DSPI timings.

Table 24. DSPI Modules AC Timing Specifications

| Name | Characteristic                                    | Min               | Max                 | Unit |
|------|---------------------------------------------------|-------------------|---------------------|------|
| DS1  | DSPI_CS[3:0] to DSPI_CLK                          | $1 \times t_{ck}$ | $510 \times t_{ck}$ | ns   |
| DS2  | DSPI_CLK high to DSPI_DOUT valid.                 | —                 | 12                  | ns   |
| DS3  | DSPI_CLK high to DSPI_DOUT invalid. (Output hold) | 2                 | —                   | ns   |
| DS4  | DSPI_DIN to DSPI_CLK (Input setup)                | 10                | —                   | ns   |
| DS5  | DSPI_DIN to DSPI_CLK (Input hold)                 | 10                | —                   | ns   |

The values in Table 24 correspond to Figure 30.

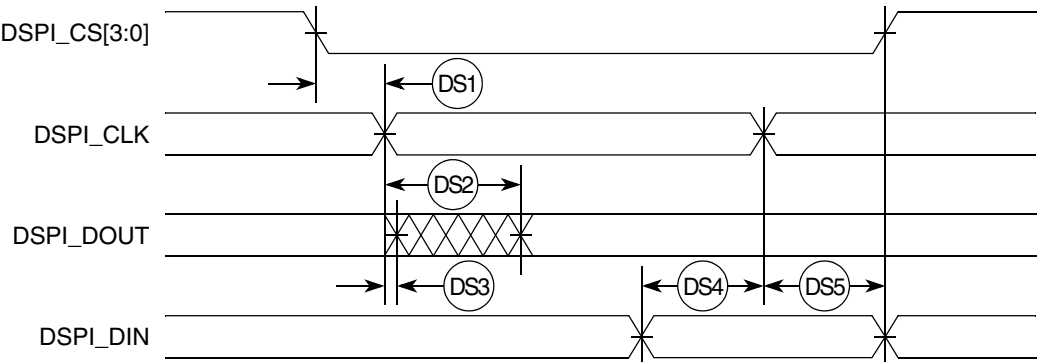


Figure 30. DSPI Timing

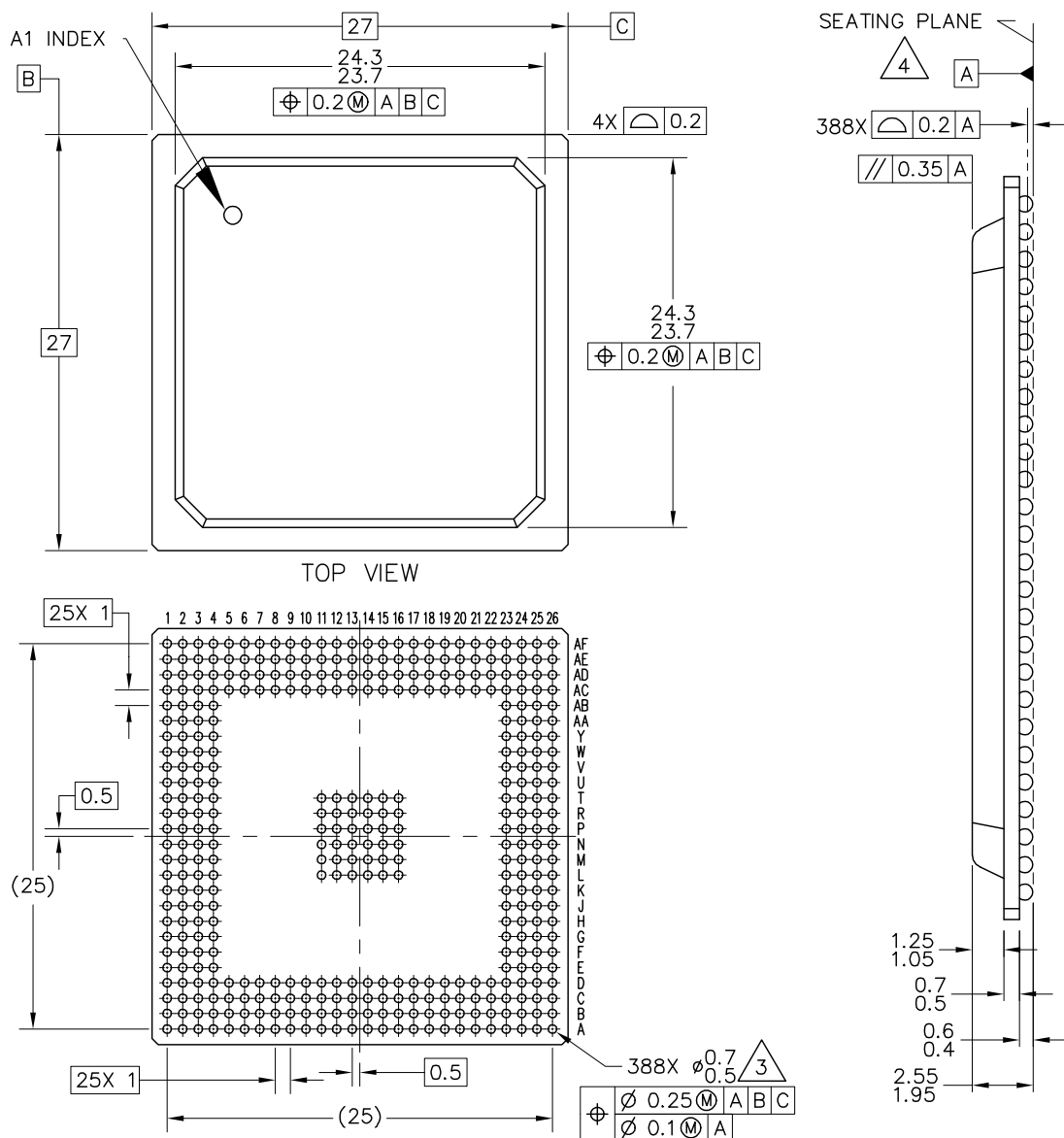
# 16 Timer Module AC Timing Specifications

Table 25 lists timer module AC timings.

Table 25. Timer Module AC Timing Specifications

| Name | Characteristic                        | 0–66 MHz |     | Unit   |
|------|---------------------------------------|----------|-----|--------|
|      |                                       | Min      | Max |        |
| T1   | TIN0 / TIN1 / TIN2 / TIN3 cycle time  | 3        | —   | PSTCLK |
| T2   | TIN0 / TIN1 / TIN2 / TIN3 pulse width | 1        | —   | PSTCLK |

## 17 Case Drawing



|                                                               |  |             |  |                              |  |                            |             |           |  |
|---------------------------------------------------------------|--|-------------|--|------------------------------|--|----------------------------|-------------|-----------|--|
| © FREESCALE SEMICONDUCTOR, INC.<br>ALL RIGHTS RESERVED.       |  | BOTTOM VIEW |  | MECHANICAL OUTLINE           |  | PRINT VERSION NOT TO SCALE |             | SIDE VIEW |  |
| TITLE:<br>388 I/O, PBGA<br>27 X 27 PKG,<br>1 MM PITCH (OMPAC) |  |             |  | DOCUMENT NO: 98ARS23880W     |  |                            | REV: C      |           |  |
|                                                               |  |             |  | CASE NUMBER: 1164-02         |  |                            | 25 JAN 2007 |           |  |
|                                                               |  |             |  | STANDARD: JEDEC MS-034 AAL-1 |  |                            |             |           |  |

NOTES:

- 1. ALL DIMENSIONS IN MILLIMETERS.
- 2. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.
- 3. MAXIMUM SOLDER BALL DIAMETER MEASURED PARALLEL TO DATUM A.
- 4. DATUM A, THE SEATING PLANE, IS DETERMINED BY THE SPHERICAL CROWNS OF THE SOLDER BALLS.
- 5. PACKAGE CODES:
  - 5254 - 2 LAYER SUBSTRATE PACKAGE
  - 5367 - 4 LAYER SUBSTRATE PACKAGE

|                                                               |  |                              |  |                            |  |
|---------------------------------------------------------------|--|------------------------------|--|----------------------------|--|
| © FREESCALE SEMICONDUCTOR, INC.<br>ALL RIGHTS RESERVED.       |  | MECHANICAL OUTLINE           |  | PRINT VERSION NOT TO SCALE |  |
| TITLE:<br>388 I/O, PBGA<br>27 X 27 PKG,<br>1 MM PITCH (OMPAC) |  | DOCUMENT NO: 98ARS23880W     |  | REV: C                     |  |
|                                                               |  | CASE NUMBER: 1164-02         |  | 25 JAN 2007                |  |
|                                                               |  | STANDARD: JEDEC MS-034 AAL-1 |  |                            |  |

Figure 31. 388-pin BGA Case Outline

# 18 Revision History

| Revision Number | Date              | Substantive Changes                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                      |
|-----------------|-------------------|----------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| 2.2             | August 29, 2005   | <a href="#">Table 7</a> : Changed C1 maximum spec from 33.3 ns to 40 ns.                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                 |
| 2.3             | August 30, 2005   | <a href="#">Table 22</a> : Changed J11 maximum from 15 ns to 20 ns.                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                      |
| 2.4             | December 14, 2005 | <a href="#">Table 10</a> : Changed FB1 maximum from 33.33 ns to 40 ns.<br><a href="#">Table 14</a> : Changed FB1 maximum from 33.33 ns to 40 ns.                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                         |
| 3               | February 20, 2007 | <a href="#">Table 4</a> : Updated DC electrical specifications, $V_{IL}$ and $V_{IH}$ .<br><a href="#">Table 6</a> : Changed FlexBus output load from 20pF to 30pF.<br>Added <a href="#">Section 4.3</a> , "General USB Layout Guidelines."                                                                                                                                                                                                                                                                                                                                                                                                                                                              |
| 4               | December 4, 2007  | <a href="#">Figure 2</a> : Changed resistor value from 10W to 10 $\Omega$<br><a href="#">Figure 3</a> : Changed note 1 in from "IVDD should not exceed EVDD, SD VDD or PLL VDD by more than 0.4V..." to "IVDD should not exceed EVDD or SD VDD by more than 0.4V..."<br><a href="#">Table 3</a> : Updated thermal information for $\theta_{JMA}$ , $\theta_{JB}$ , and $\theta_{JC}$<br><a href="#">Table 4</a> : Added input leakage current spec.<br><a href="#">Table 6</a> : Added footnote regarding pads having balanced source & sink current.<br><a href="#">Table 9</a> : Added $\overline{RSTI}$ pulse duration spec.<br>Added features list, pinout drawing, block diagram, and case outline. |

THIS PAGE INTENTIONALLY BLANK

## How to Reach Us:

### Home Page:

[www.freescale.com](http://www.freescale.com)

### Web Support:

<http://www.freescale.com/support>

### USA/Europe or Locations Not Listed:

Freescale Semiconductor, Inc.  
Technical Information Center, EL516  
2100 East Elliot Road  
Tempe, Arizona 85284  
+1-800-521-6274 or +1-480-768-2130  
[www.freescale.com/support](http://www.freescale.com/support)

### Europe, Middle East, and Africa:

Freescale Halbleiter Deutschland GmbH  
Technical Information Center  
Schatzbogen 7  
81829 Muenchen, Germany  
+44 1296 380 456 (English)  
+46 8 52200080 (English)  
+49 89 92103 559 (German)  
+33 1 69 35 48 48 (French)  
[www.freescale.com/support](http://www.freescale.com/support)

### Japan:

Freescale Semiconductor Japan Ltd.  
Headquarters  
ARCO Tower 15F  
1-8-1, Shimo-Meguro, Meguro-ku,  
Tokyo 153-0064  
Japan  
0120 191014 or +81 3 5437 9125  
[support.japan@freescale.com](mailto:support.japan@freescale.com)

### Asia/Pacific:

Freescale Semiconductor Hong Kong Ltd.  
Technical Information Center  
2 Dai King Street  
Tai Po Industrial Estate  
Tai Po, N.T., Hong Kong  
+800 2666 8080  
[support.asia@freescale.com](mailto:support.asia@freescale.com)

### For Literature Requests Only:

Freescale Semiconductor Literature Distribution Center  
P.O. Box 5405  
Denver, Colorado 80217  
1-800-441-2447 or 303-675-2140  
Fax: 303-675-2150  
[LDCForFreescaleSemiconductor@hibbertgroup.com](mailto:LDCForFreescaleSemiconductor@hibbertgroup.com)

Document Number: MCF5475EC

Rev. 4

12/2007

Information in this document is provided solely to enable system and software implementers to use Freescale Semiconductor products. There are no express or implied copyright licenses granted hereunder to design or fabricate any integrated circuits or integrated circuits based on the information in this document.

Freescale Semiconductor reserves the right to make changes without further notice to any products herein. Freescale Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does Freescale Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation consequential or incidental damages. "Typical" parameters that may be provided in Freescale Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals", must be validated for each customer application by customer's technical experts. Freescale Semiconductor does not convey any license under its patent rights nor the rights of others. Freescale Semiconductor products are not designed, intended, or authorized for use as components in systems intended for surgical implant into the body, or other applications intended to support or sustain life, or for any other application in which the failure of the Freescale Semiconductor product could create a situation where personal injury or death may occur. Should Buyer purchase or use Freescale Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hold Freescale Semiconductor and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that Freescale Semiconductor was negligent regarding the design or manufacture of the part.

RoHS-compliant and/or Pb-free versions of Freescale products have the functionality and electrical characteristics as their non-RoHS-compliant and/or non-Pb-free counterparts. For further information, see <http://www.freescale.com> or contact your Freescale sales representative.

For information on Freescale's Environmental Products program, go to <http://www.freescale.com/epp>.

Freescale™ and the Freescale logo are trademarks of Freescale Semiconductor, Inc. All other product or service names are the property of their respective owners.  
© Freescale Semiconductor, Inc. 2007. All rights reserved.